

USB Type-C Design Implementations – Overview & Test Solution

Seo Dong-Hyun





USB Type-C Overview

What is the USB Type-C Connector?

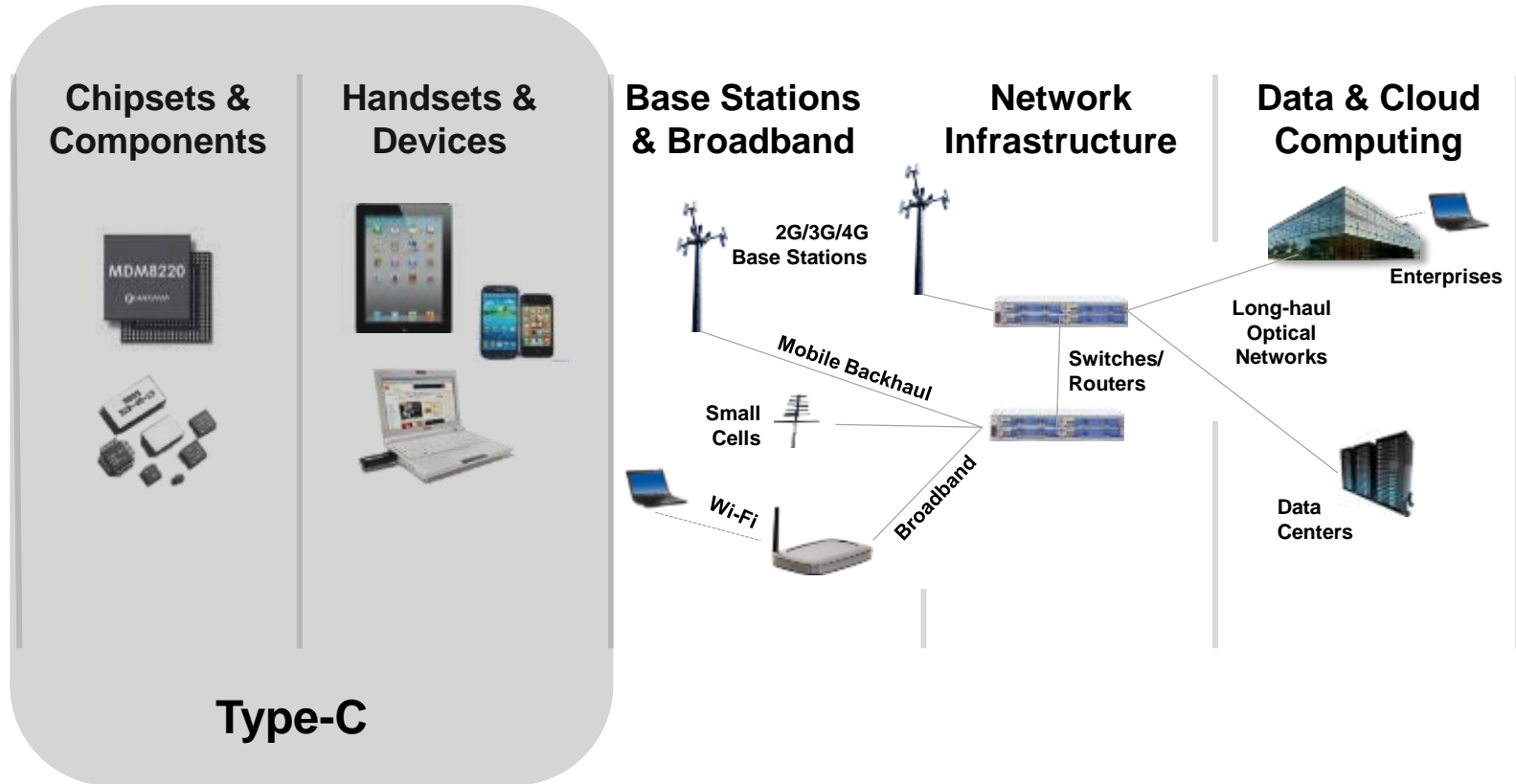
“One connector to rule them all”



Original USB Industry Drivers	Type-C Industry Drivers
Single connector type/Expandability	Broad application in standards
Performance/Speed	10 Gb/s with path to 40 Gb/s
Power	Can handle 5 Amps at 20Volts
Ease of Use for End-User	Reversible (can be flipped)

The Communications Ecosystem

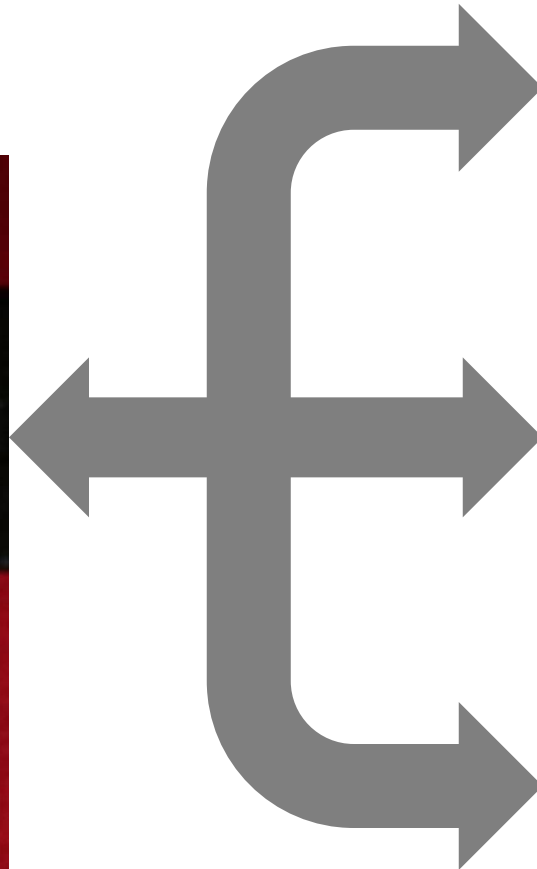
Where does USB-C fit?



Why Does It Matter?

Simplicity and Capability to consumer....

.....Complexity to Designers, Integrators, and Validators



Speed

Speeds of the Future and Backwards Compatibility

Power

Up to 100 W
Power direction no longer fixed



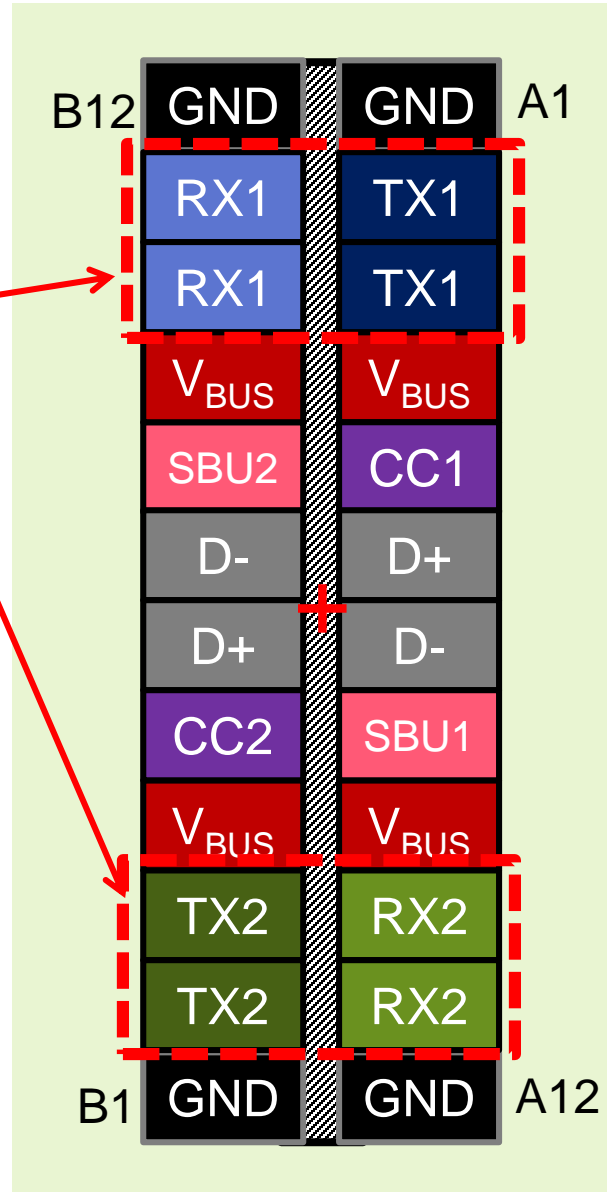
Standards Integration



USB Type C Signal Plan

High Speed Lanes

4 High Speed Lanes:
Up to 20Gbs each

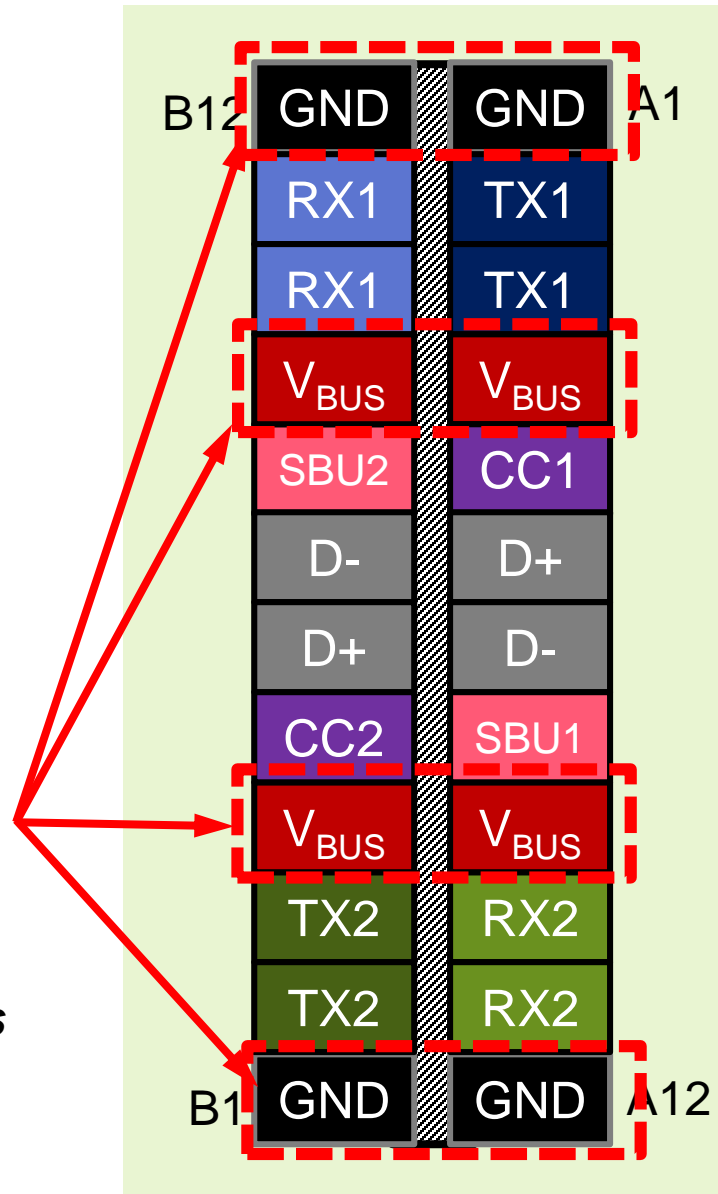


Port 1

Port 2

USB Type C Signal Plan

Power Pins

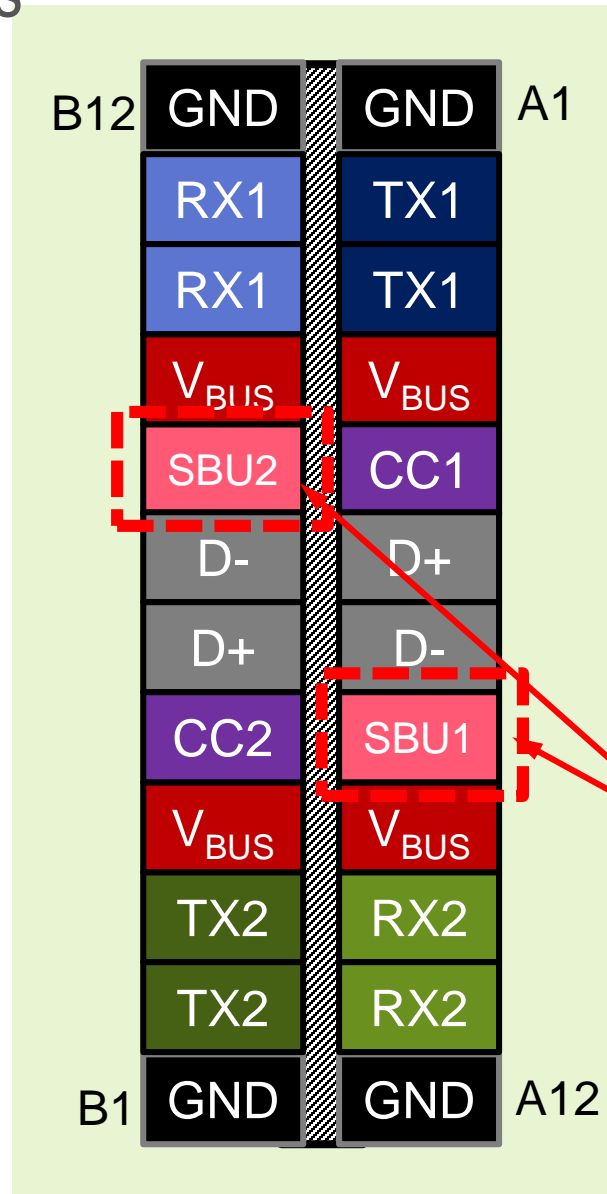


Power Pins

- 4 GND
 - 4 Supply Pins
- Handles up to 5 amps*

USB Type C Signal Plan

Sideband Use Pins

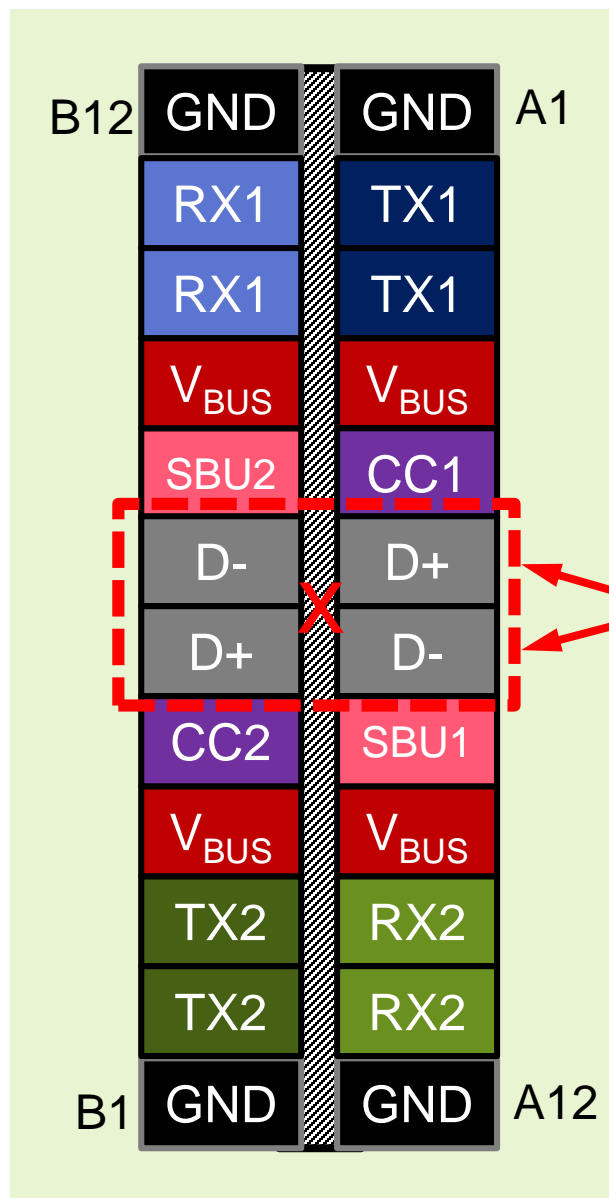


SBU lines:

- Extra lines for alternate use

USB Type C Signal Plan

USB2.0 Pins

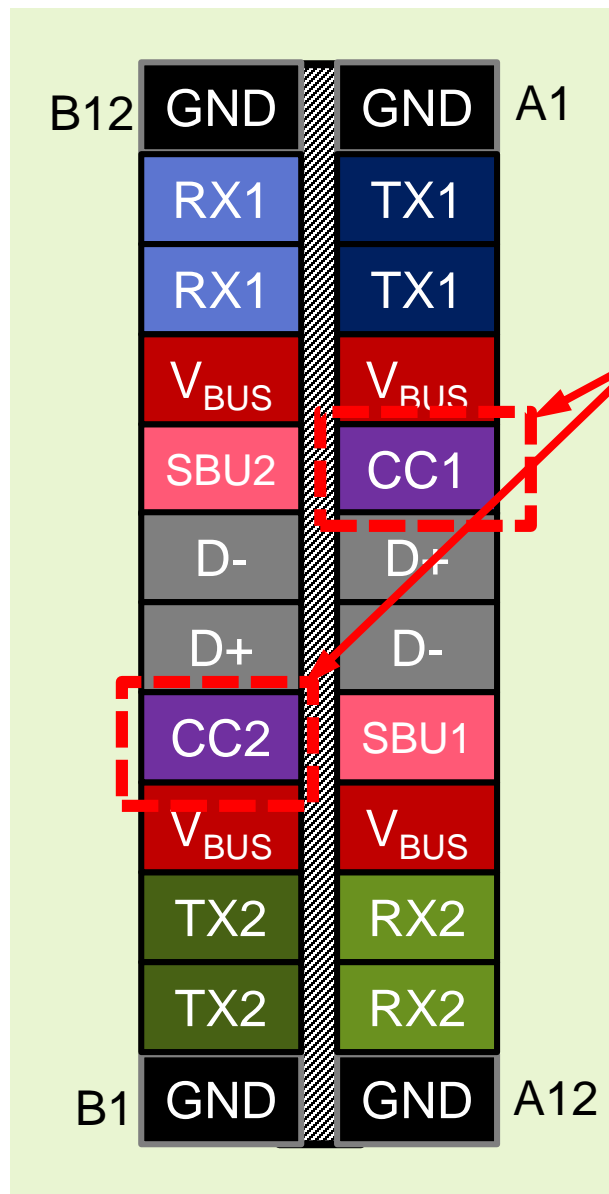


USB2 lines:

- USB2 operation
- Link Communication

USB Type C Signal Plan

CC Pins

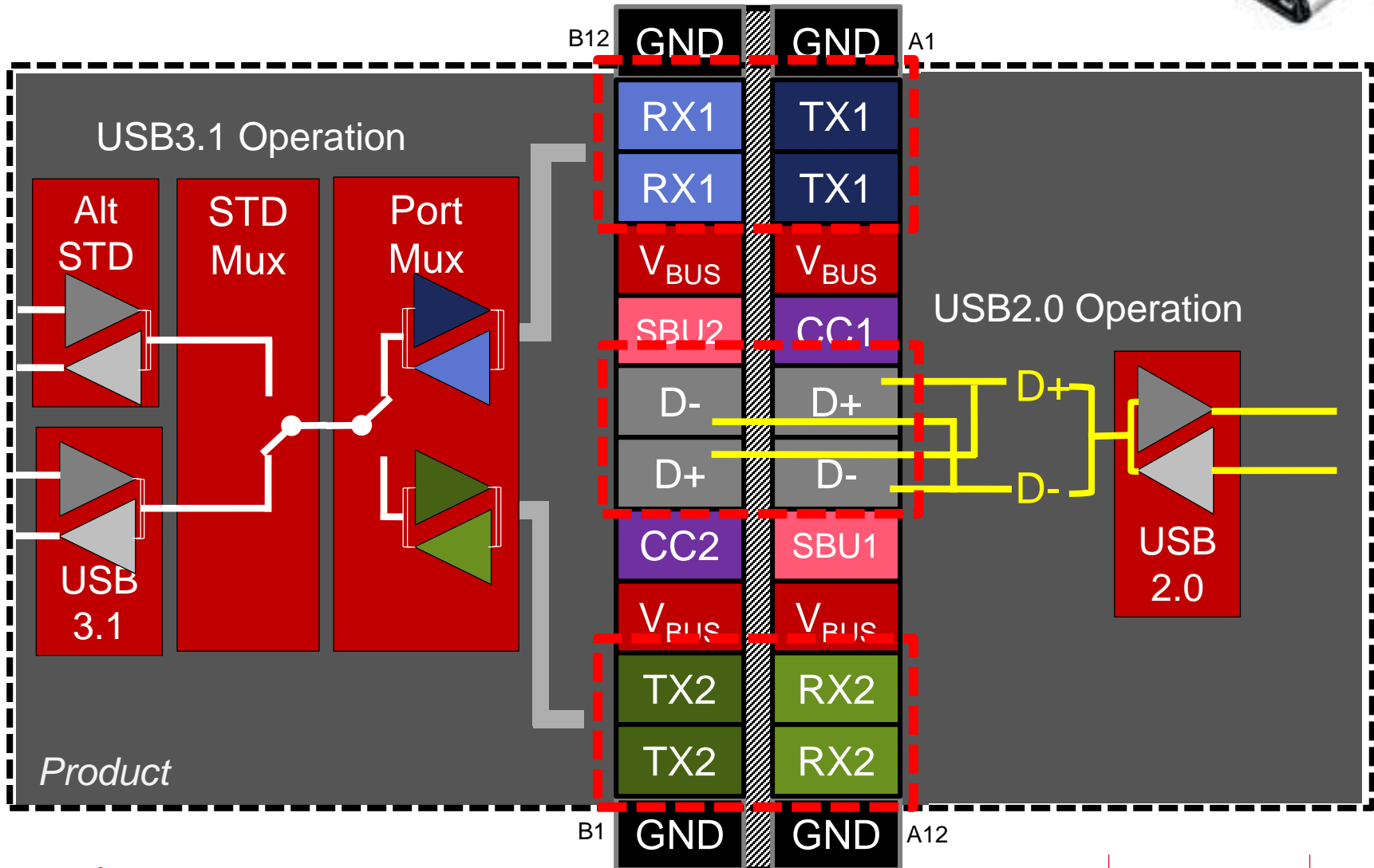


CC lines for:

- Configuration Mngmt,
- Supply Power to Cable
- Power Delivery Communication

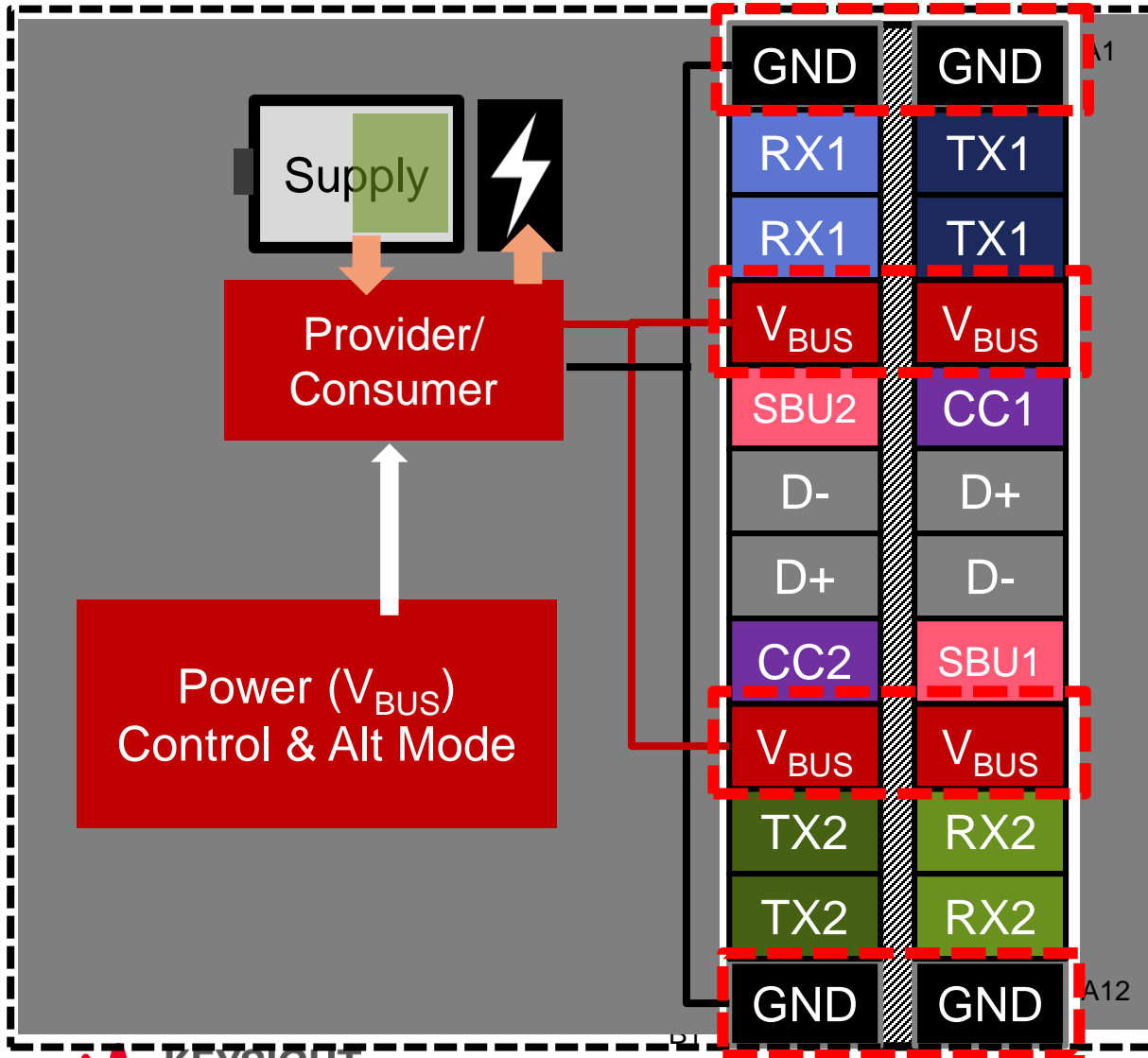
USB Type C Port Function

USB3.1 & USB2.0



USB Type C Port Function

Power Lines



USB Type C Port Function

SBU Lines (Sideband Use)



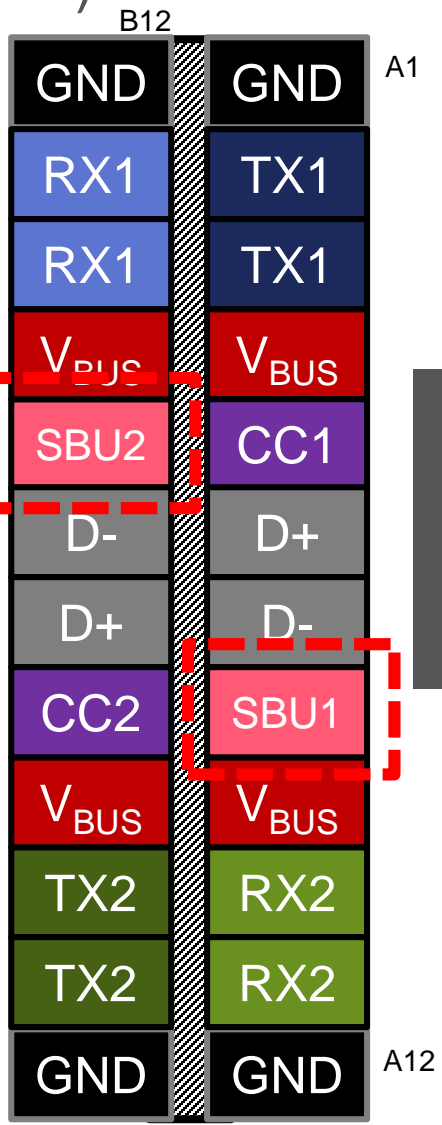
SBU lines NOT used in USB3.1
Become active in alternate mode
only to support the alternate
technology.

DisplayPort

SBU1 -> AUX +
SBU2 -> AUX -

Thunderbolt

SBU1 -> LSRX
SBU2 -> LSTX



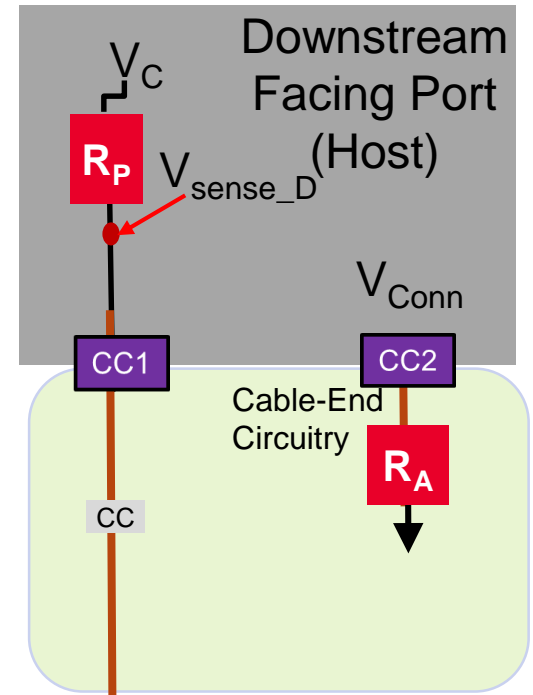
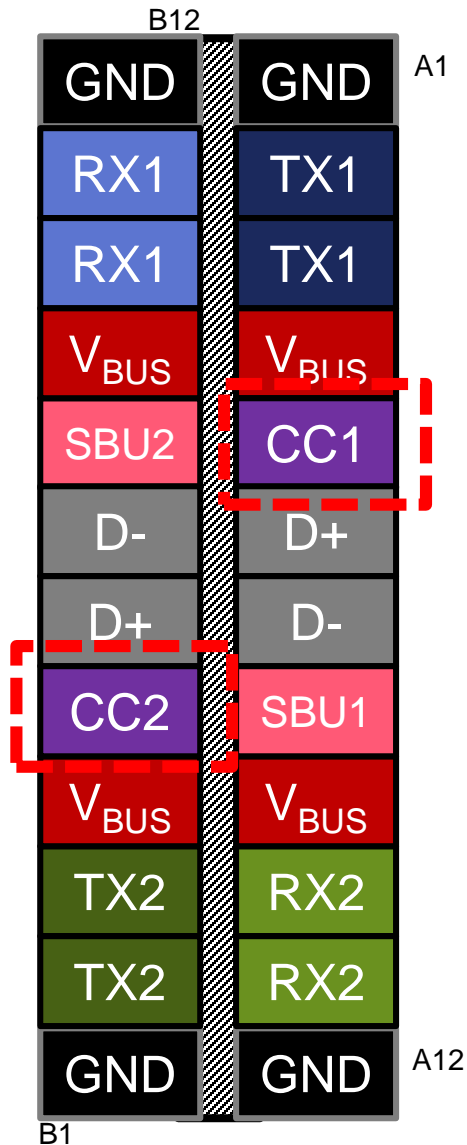
MHL

SBU1 -> e-CBUS-S
SBU2 -> e-CBUS-S

USB Type C Port Function

CC Lines (Configuration Channel)

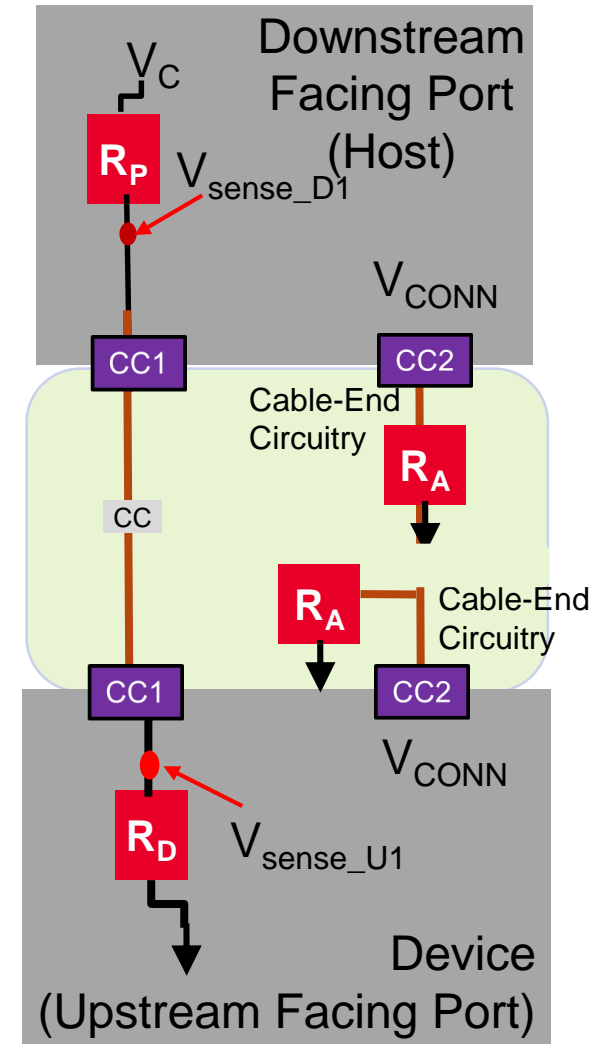
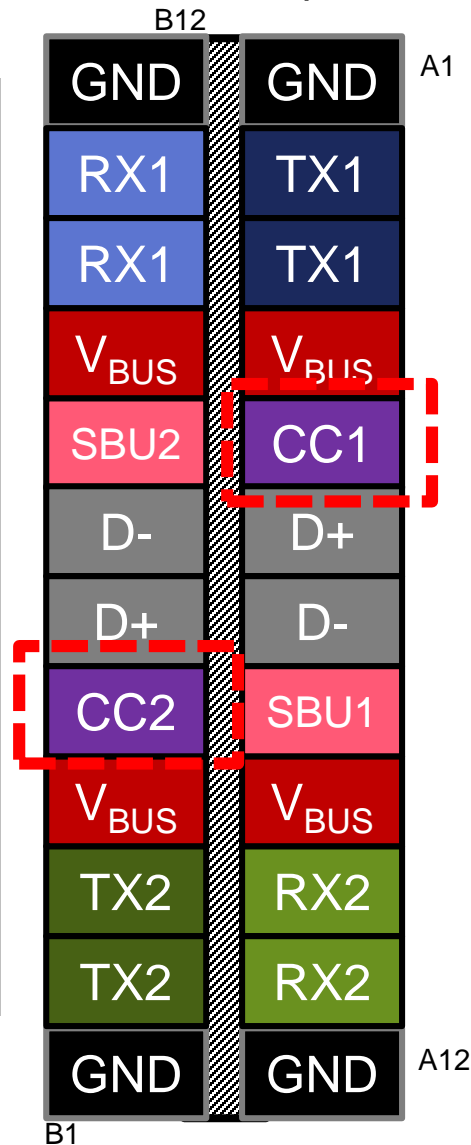
CC1 and CC2 Sensed for Termination:
 If cable termination (R_A) is present at CCn Then
 $CCn \Rightarrow V_{CONN}$



USB Type C Port Function

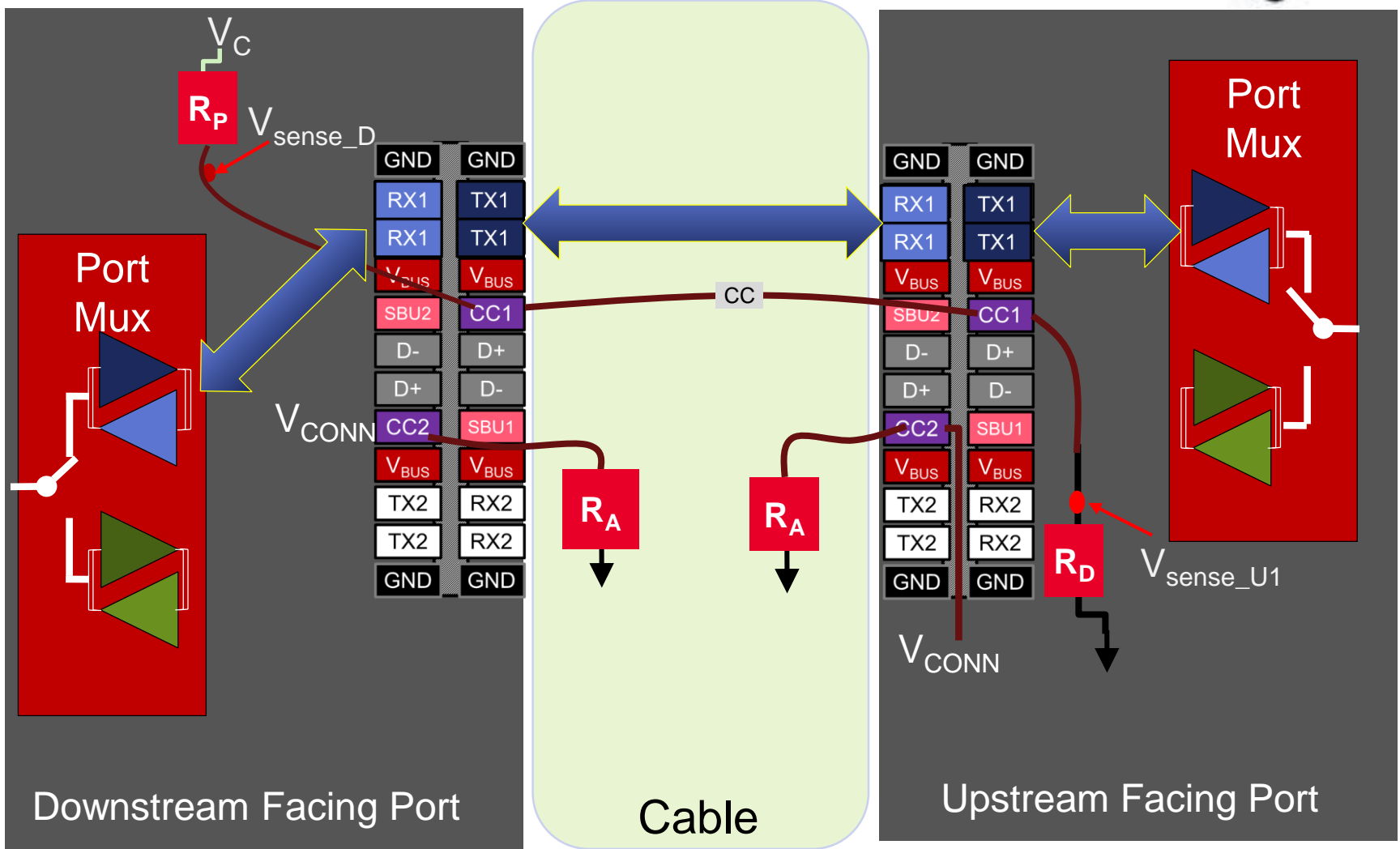
CC Lines (Configuration Channel)

CC1 and CC2 Sensed for Termination:
 If cable termination (R_A) is present at CCn Then
 $CCn \Rightarrow V_{CONN}$
 Else
 When Link partner terminated then
 Port orientations are known and CC Line becomes the power delivery channel.



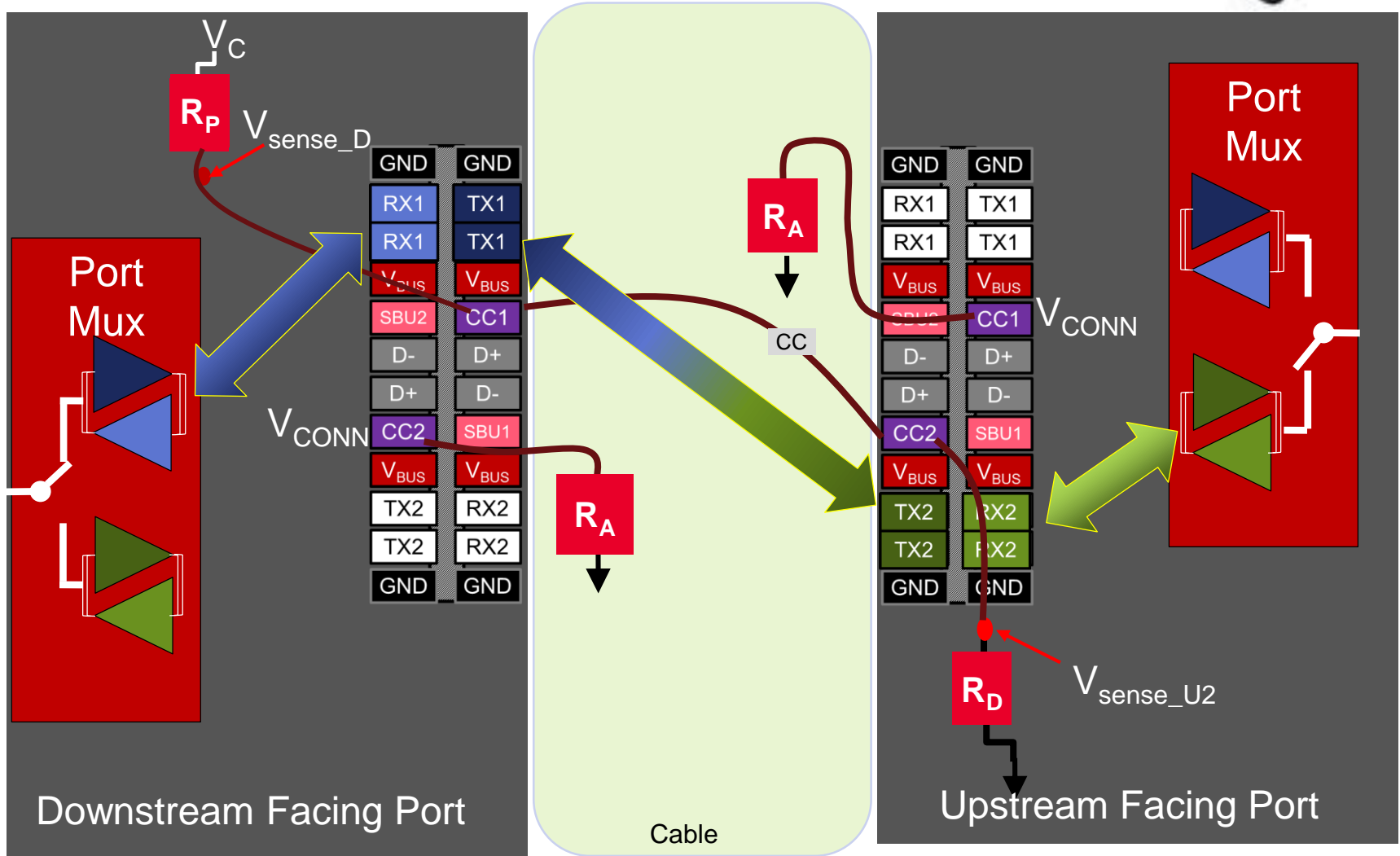


USB Type C Port Function Port Configuration

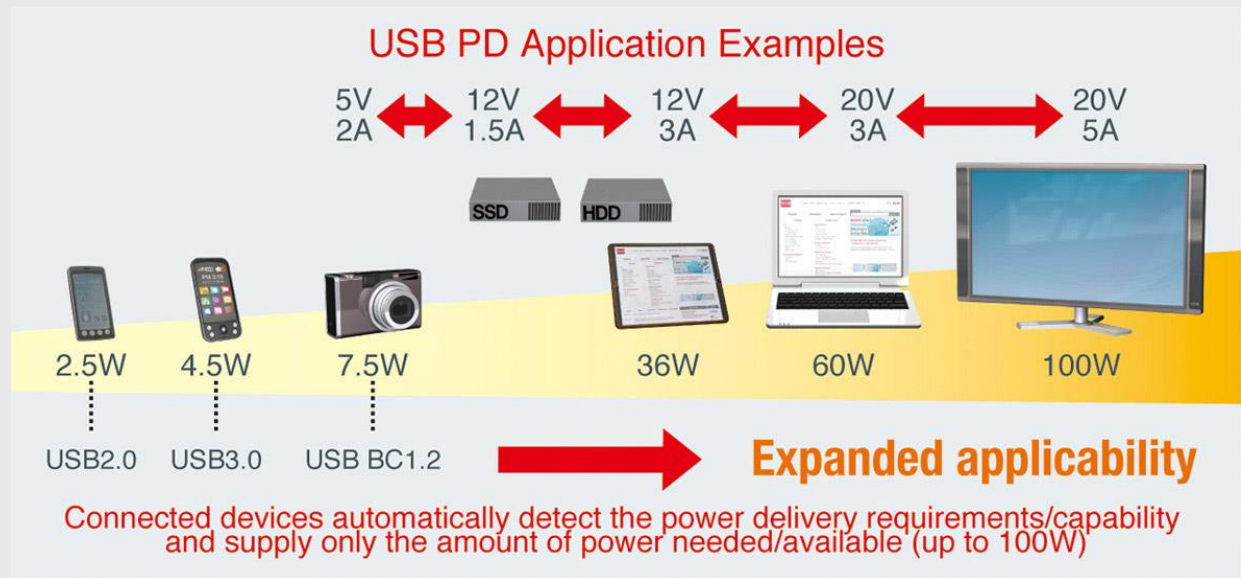


USB Type C Port Function

Port Configuration (Cable Flip at UFP)

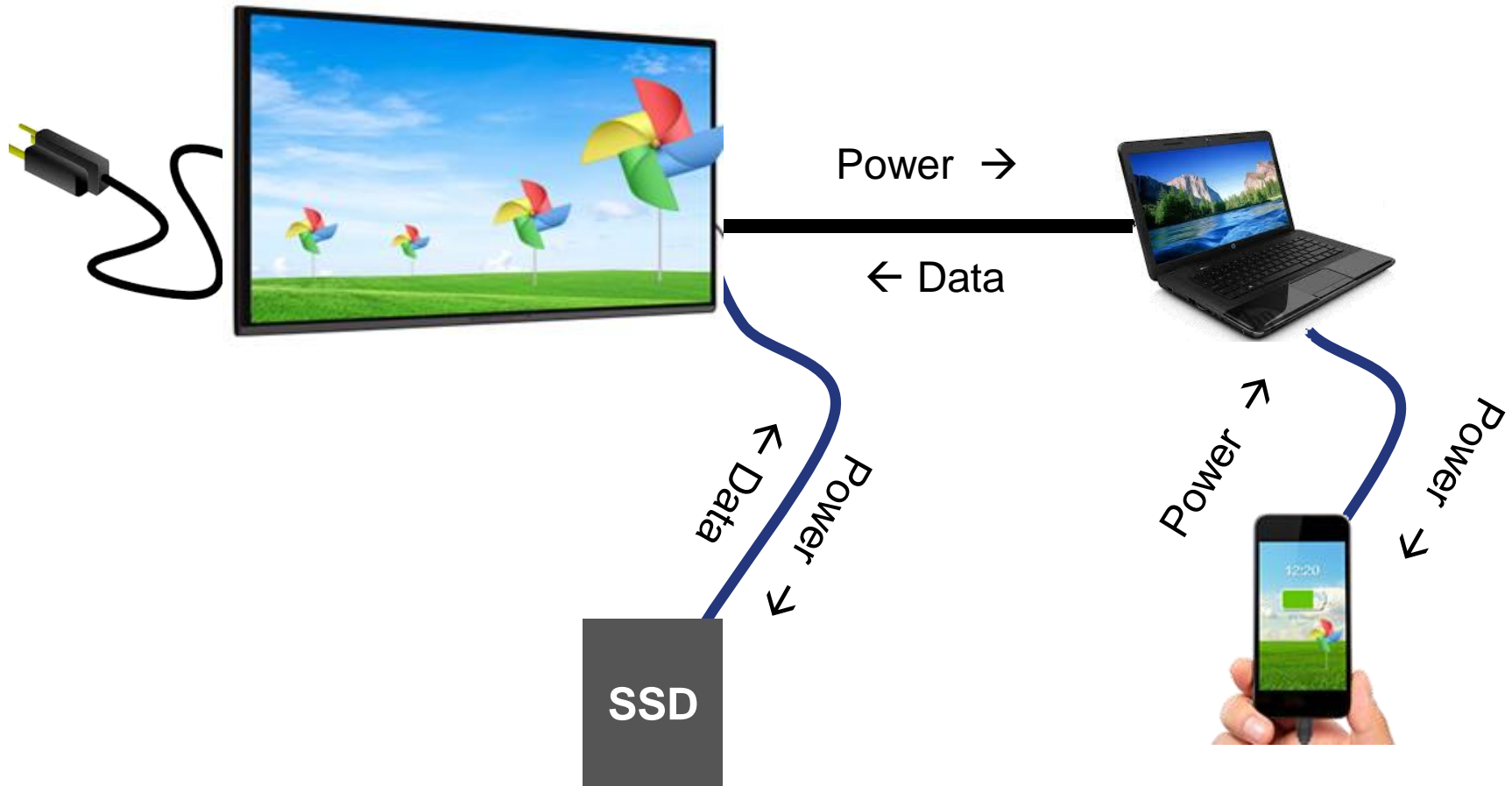


USB Type-C PD (Power Delivery) Validation Solutions



USB Power Delivery Example

Only 1 traditional wall power cord



USB-PD Specification Test Plan




Three Test Sections

Power Delivery Compliance Plan
for the Power Delivery Specification Revision 1.0
Version 2.0

Version 0.900 (V2.0)
29 Oct 2015

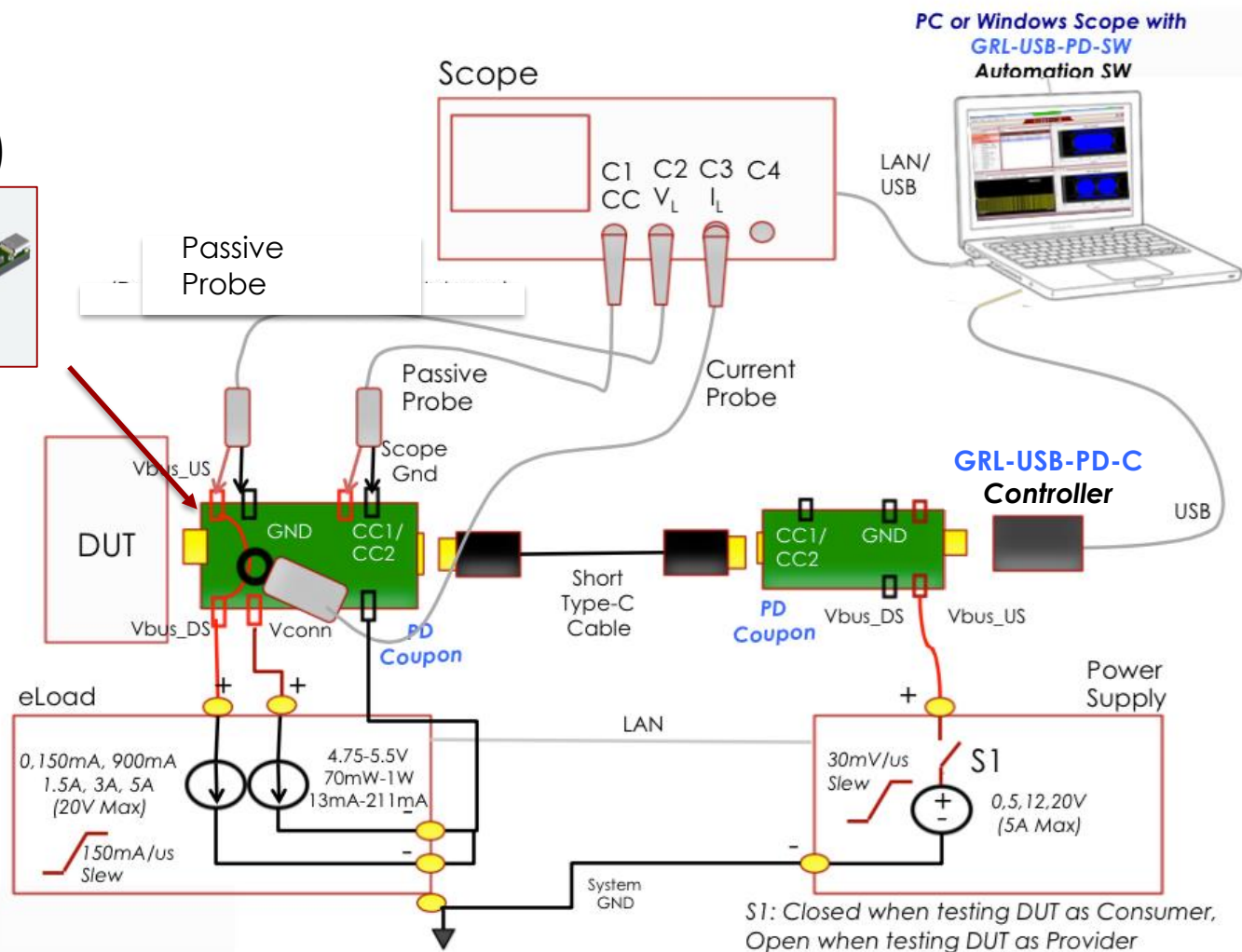
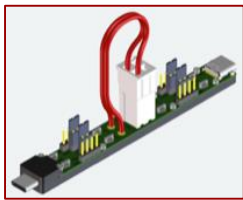
Power Delivery Compliance Plan

11	COMMON TEST PROCEDURES	209
11.1	BMC-PROC-PD-MODE: Getting into PD Mode	209
11.1.1	UUT initially a DFP (Source) or a DRP initially connected to a Tester (Sink)	209
11.1.2	UUT initially a UFP (Sink) or a DRP initially connected to a Tester (Source)	210
11.2	Hard Reset Monitoring	211
12	TEST OVERVIEW	212
12.1	Cable Markers - Primary Tests	212
12.1.1	Physical Layer - Transmit	212
12.1.2	Physical Layer - Receive	212
12.1.3	Physical Layer - Miscellaneous	212
12.1.4	Protocol Specific	212
12.2	Power Delivery Devices - Primary Tests	213
12.2.1	Physical Layer - Transmit	213
12.2.2	Physical Layer - Receive	213
12.2.3	Physical Layer - Miscellaneous	213
12.2.4	Protocol Specific	213
12.2.1	Power Source/Sink	214
12.3	All Devices - Secondary Checks	215
12.3.1	Message Checks	215
12.3.2	Procedures and Procedure Checks	216
13	TEST DESCRIPTIONS	218
13.1	CHAPTER 3 - CABLE AND CONNECTOR TESTS	218

	12.1	Cable Markers - Primary Tests	212
	12.2	Power Delivery Devices - Primary Tests	213
	12.3	All Devices - Secondary Checks	215

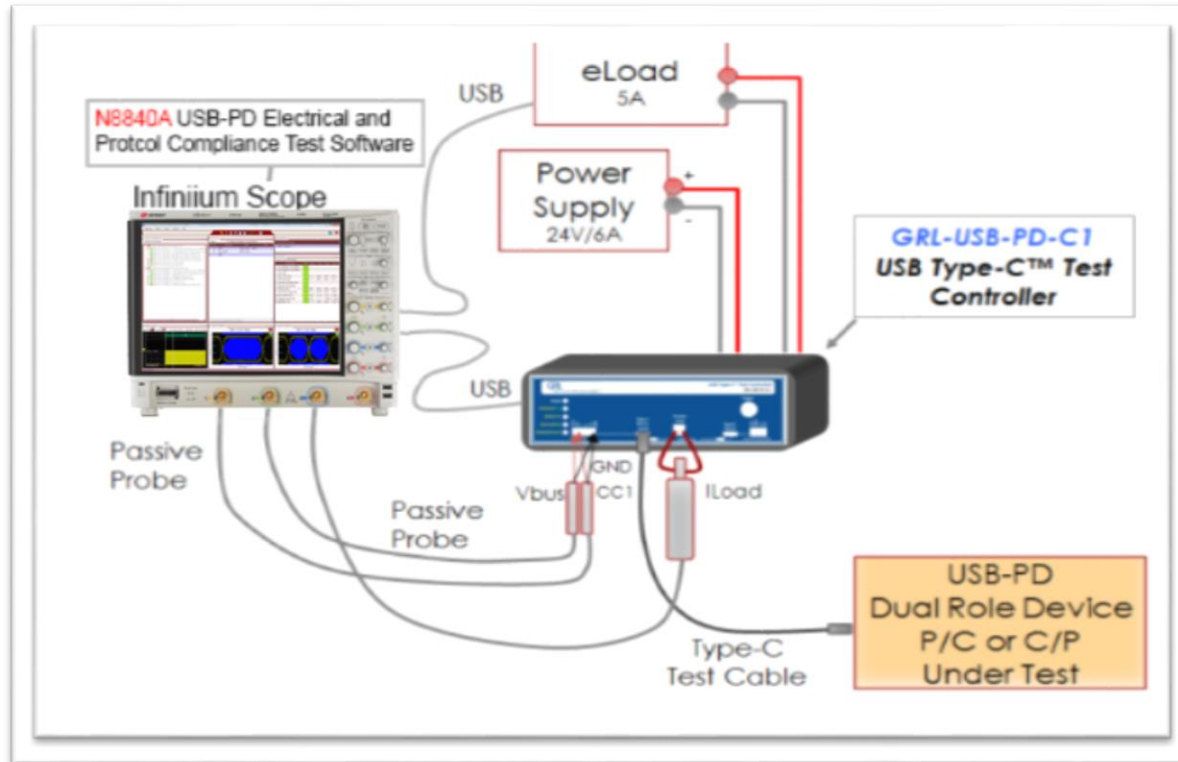
Chapter 5: Physical Layer Test (Provider/Consumer)

USB-PD
Coupon(s)



USB-PD Device Testing using N8840A

Test setup – Dual Role Devices (P/C or C/P)

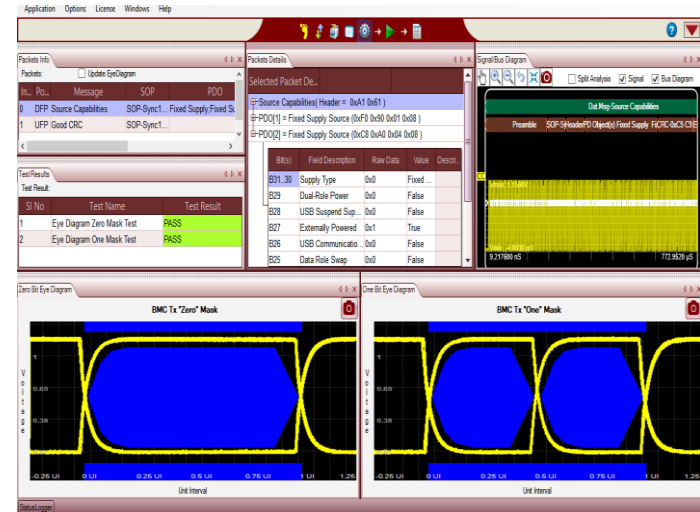


- Requires electrical load (eLoad) and current probe for load test
- SMPS Power Adapter will be sufficient however an external power supply is recommended if a clean power source is needed for Vconn

N8840A USB-PD Electrical and Protocol Compliance Test Software

Power Delivery Compliance Testing

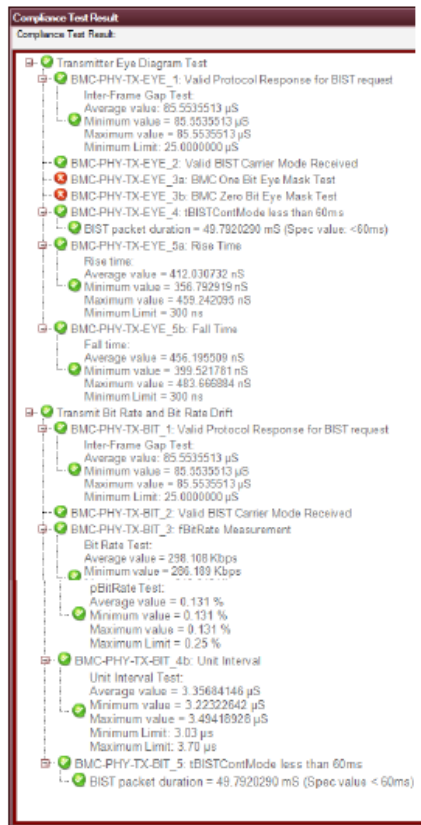
- Runs on Infiniium based oscilloscopes
 - S-Series recommended for hardware protocol trigger
- Performs BMC-PHY Compliance tests
- Performs BMC-PROT Compliance tests
- Performs BMC-POW Compliance tests
- Automates Compliance tests when used with Type-C Test Controller
- Developed in partnership with GRL (Granite River Labs)



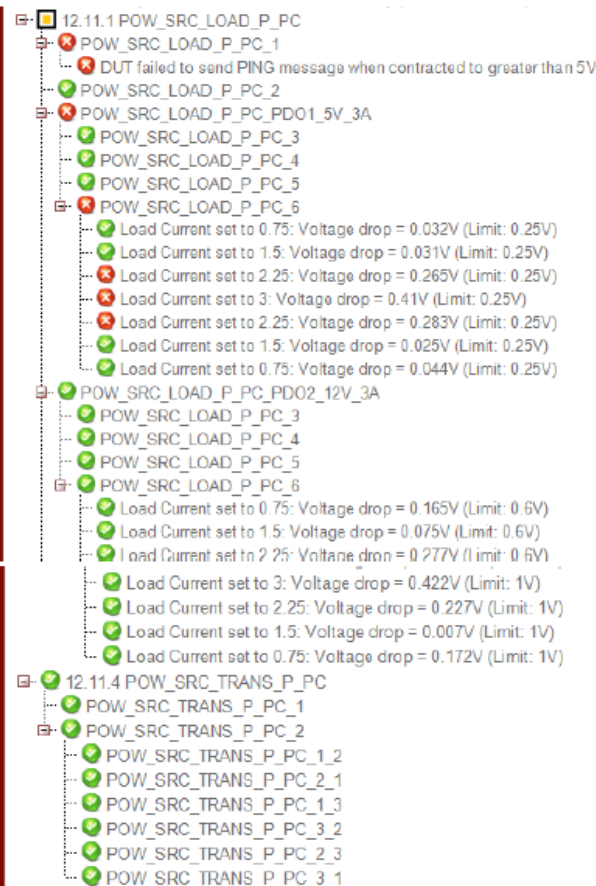
USB-PD Device Testing using N8840A

Compliance Test Results

BMC PHY

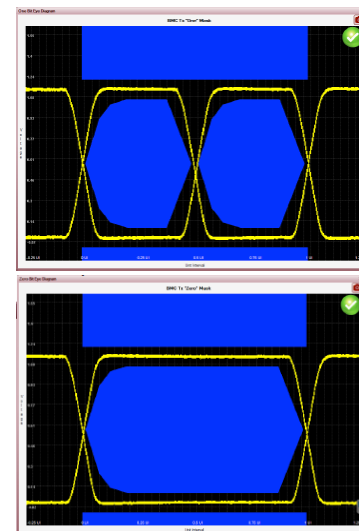


Power Loads and Transitions



Power Role Swap

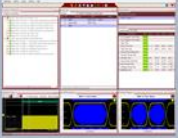



- ✓ POW_SWAP_PC_SRC_REQ
- ✓ PROC_PD_MODE
- ✗ PROT_PROC_SWAP_UUT_SRC
 - ✗ UUT could not initiate Power Role Swap
- ✓ POW_SWAP_PC_SNK_SRC
- ✓ PROC-PD-MODE
- ✓ PROT-PROC-SWAP-TSTR-SNK
- ✓ PROT-PROC-SWAP-TSTR-SRC
- ✓ POW_SWAP_PC_SNK_SNK
- ✓ PROC-PD-MODE
- ✓ PROT-PROC-SWAP-TSTR-SNK
- ✗ PROT-PROC-SWAP-UUT-SNK



PD Compliance Test Configuration

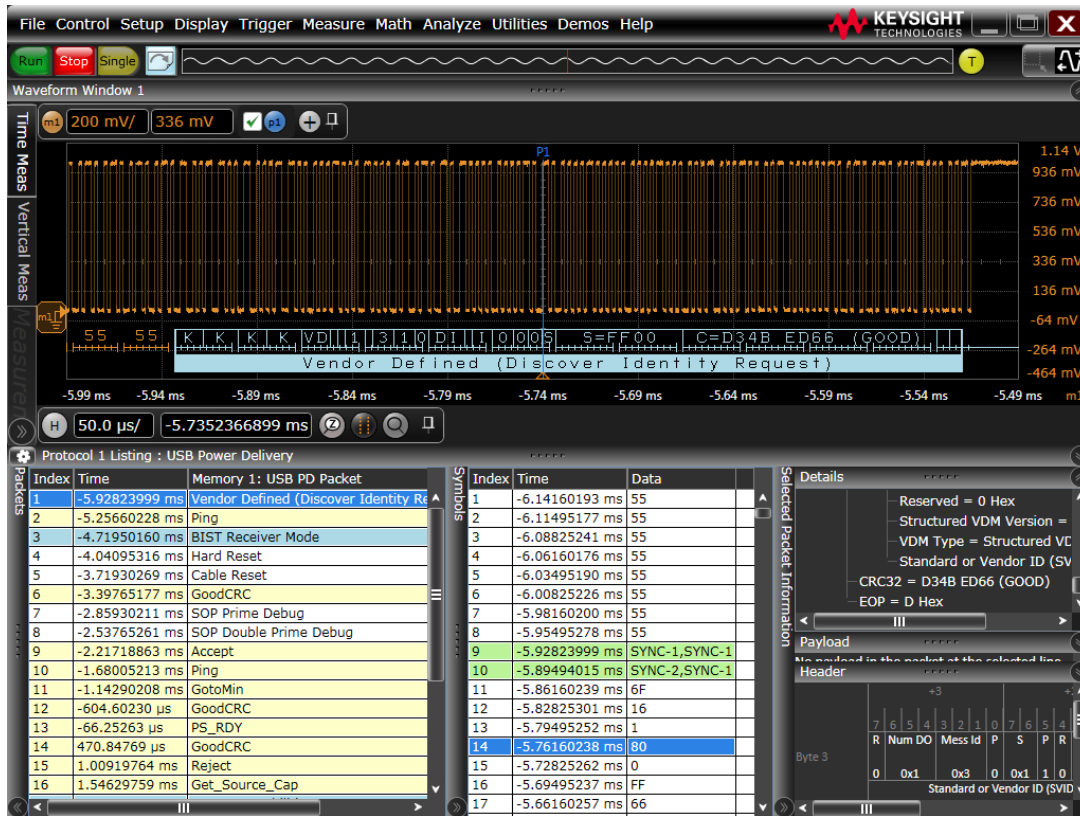
Dual Role Port (DRP) Test

Recommended Scope	Scope	Probe	
S-Series	 x1	 x2 Passive Probe 10:1 500 MHz x2 N2873A (included with scope)	 1147A or N2893A x1
Compatible Scopes	Scope	Probe Adapters	
9000 Series	 x1	Passive Probe 10:1 500 MHz x2 N2873A (included with scope)	
90000X / V-Series	 x1	 High Impedance Adapter N5449A (includes passive probe) x 2	
Q-Series	 x1		
90000Q / Z-Series	 x1		
90000A Series	 x1	 x 2 E2697A x 2	 N2782B and N2279A

Required Products	
	N8840A x1
	PD controller x1 (GRL-USB-PD-C1)
	N3301A x1 eLoad Mainframe
	N3303A x1 250W eLoad Module
	82357B x1 USB/GPIB Cable
	PD coupon x1 (USB3.1-C-PDC)

N8837A USB-PD Protocol Trigger and Decode

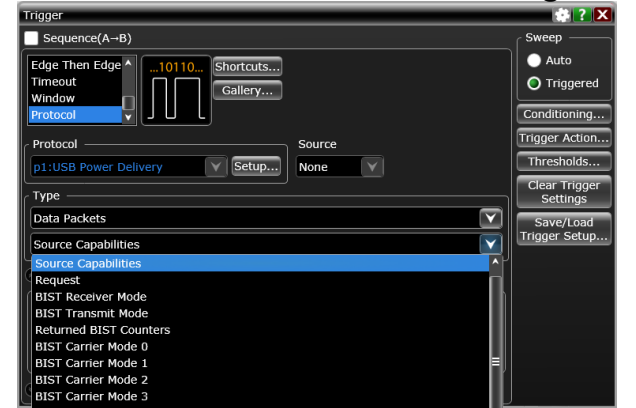
Keysight Power Delivery protocol decode and hardware triggering with S-Series



USB PD protocol decoding window example



USB PD CC and Vbus line signal

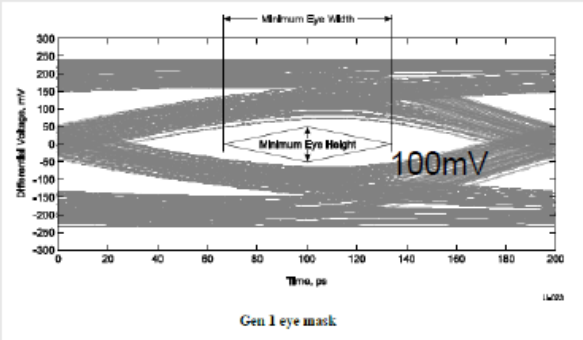
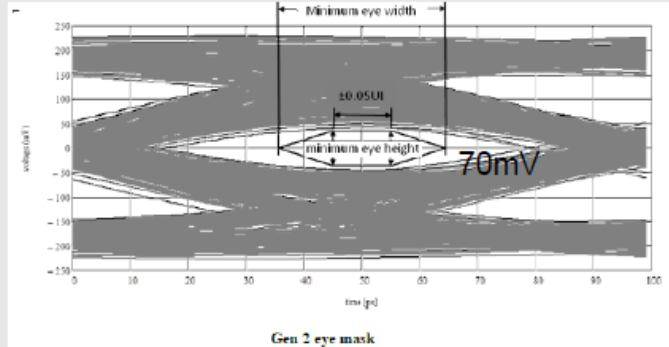


Hardware serial trigger in S-Series

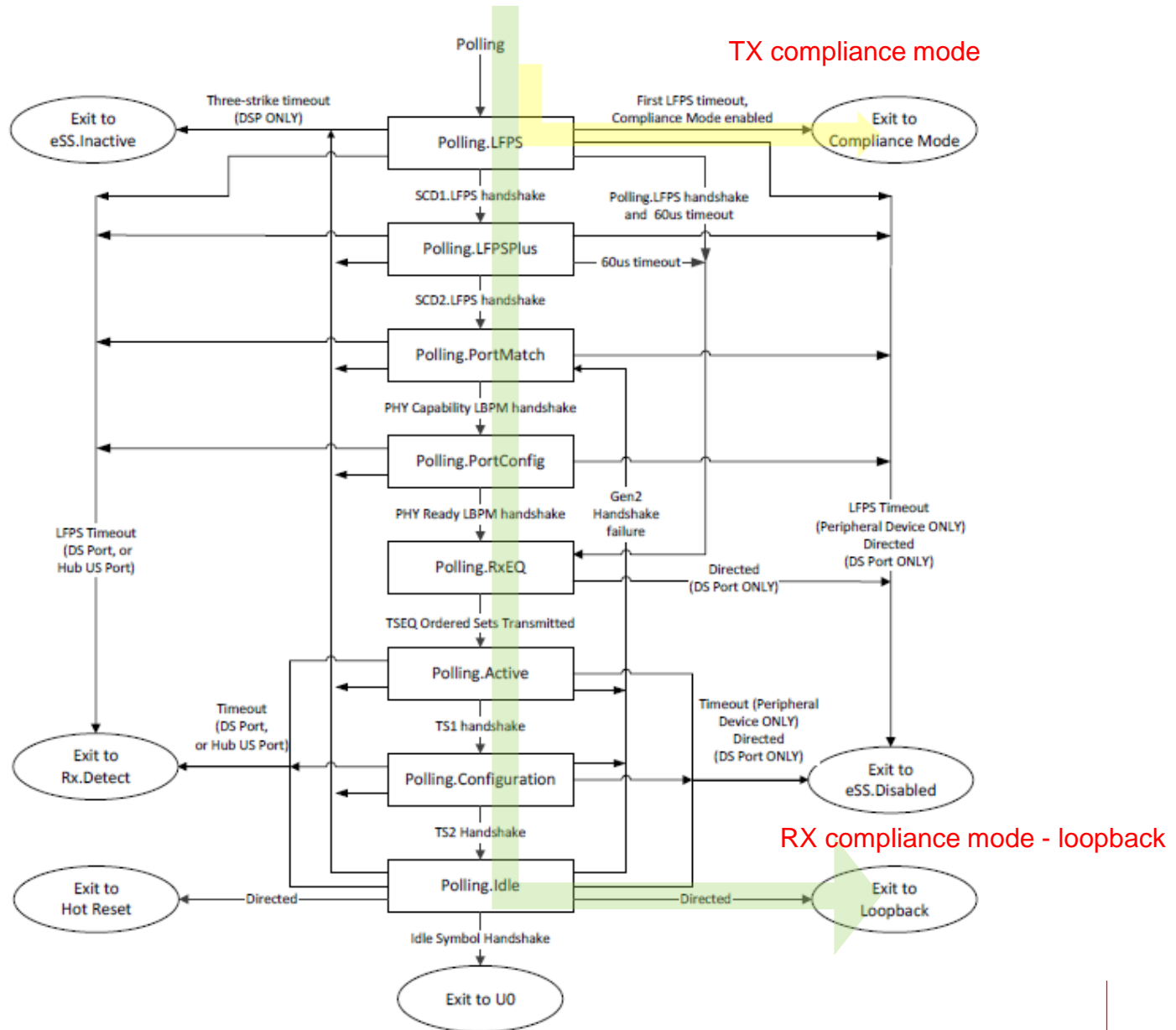


USB 3.1 Overview

USB 3.1 Gen1 and Gen2

	Gen1	Gen2
Data rate	5 Gb/s	10 Gb/s
Encoding	8b/10b	128b/132b (20% additional bandwidth over 8b/10b)
Tx REF EQ	Normative Post: -3 dB	Informative Pre: 2.2 dB Post: -3.1 dB
Rx REF EQ	CTLE	CTLE (6 level) + 1 tap DFE
CDR (JTF BW)	4.9 MHz	7.5 MHz
Eye Height / Mask		
TJ	132 psec (0.66 UI)	71.4 psec (0.714 UI)
Target Channel	3 meter (-17 dB @ 2.5 GHz)	1 meter -23 dB @ 5 GHz

USB 3.1 LTSSM

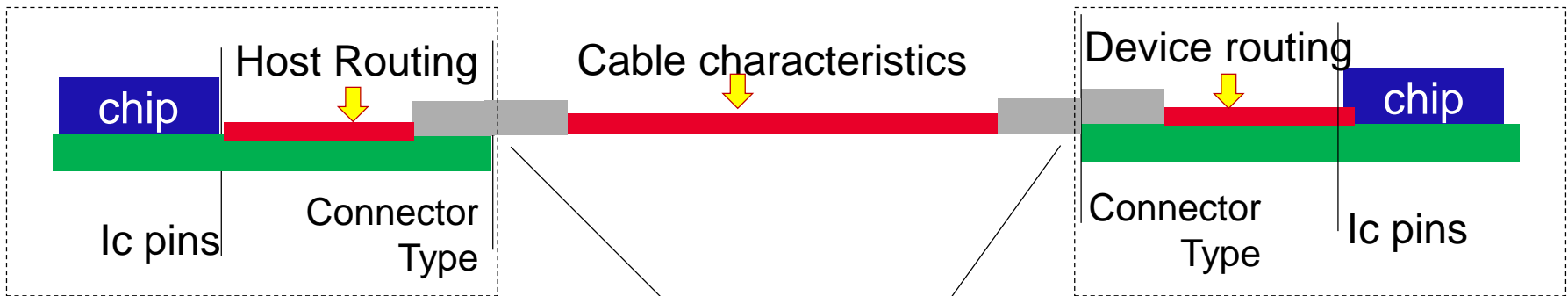
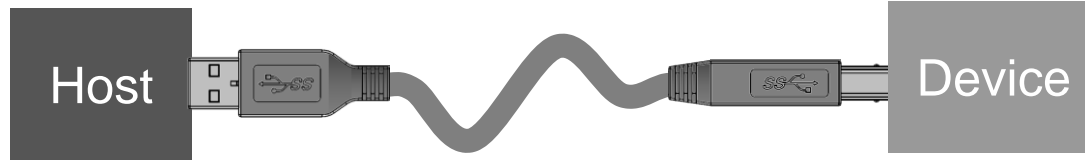


USB 3.1 Compliance Patterns

Table 6-13. Compliance Pattern Sequences

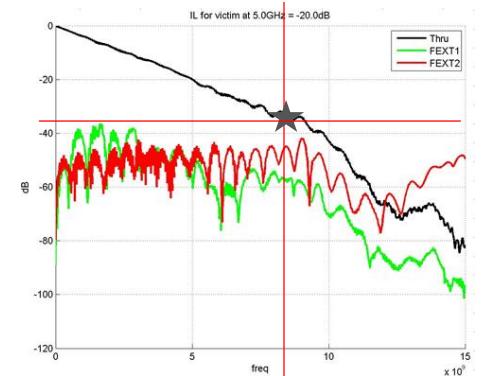
Compliance Pattern	Value	Description
CP0	D0.0 scrambled	A pseudo-random data pattern that is exactly the same as logical idle (refer to Chapter 7) but does not include SKP sequences.
CP1	D10.2	Nyquist frequency
CP2	D24.3	Nyquist/2
CP3	K28.5	COM pattern
CP4	LFPS	The low frequency periodic signaling pattern
CP5	K28.7	With de-emphasis
CP6	K28.7	Without de-emphasis
CP7	50-250 1's and 0's	With de-emphasis. Repeating 50-250 1's and then 50-250 0's.
CP8	50-250 1's and 0's	Without de-emphasis. Repeating 50-250 1's and then 50-250 0's.
CP9		Pseudo-random data pattern (see section 6.4.4.1)
CP10	AAh	Nyquist pattern at 10Gb/s. This is not 128b132b encoded.
CP11	CCh	Nyquist/2 at 10Gb/s, This is not 128b132b encoded.
CP12	LFSR15	Uncoded LFSR15 for PHY level testing and fault isolation. This is not 128b132b encoded. The polynomial is $x^{15}+x^{14}+1$.
CP13	64 1's and 0's	With pre-shoot defined in section 6.7.5.2 (no de-emphasis). Repeating 64 1's and then 64 0's at 10Gb/s. This is not 128b132b encoded.
CP14	64 1's and 0's	With de-emphasis defined in section 6.7.5.2 (no pre-shoot). Repeating 64 1's and then 64 0's at 10Gb/s. This is not 128b132b encoded.
CP15	64 1's and 0's	With pre-shoot and de-emphasis defined in section 6.7.5.2. Repeating 64 1's and then 64 0's at 10Gb/s. This is not 128b132b encoded.
CP16	64 1's and 0's	No de-emphasis or pre-shoot. Repeating 64 1's and then 64 0's at 10Gb/s. This is not 128b132b encoded.

USB3.1 Channel Budget



Loss at Nyquist is identified here. Channel Models (s-parameters) required.

Data Rate	Host	Connector	Cable	Connector	Device
5G	10dB	Std A	7.5dB	Std B	2.5dB
5G	10dB	Std A	3.5dB	Micro B	6.5dB
5G	6.5dB	C	7dB	C	6.5dB
5G	10dB	Std A	3.5dB	C	6.5dB
5G	6.5dB	C	4dB	Std B	2.5dB
5G	6.5dB	C	4dB	Micro B	6.5dB
10G	8.5dB	Std A	6dB	Std B	8.5dB
10G	8.5dB	Std A	6dB	Micro B	8.5dB
10G	8.5dB	Std A	6dB	C	8.5dB
10G	8.5dB	C	6dB	Std B	8.5dB
10G	8.5dB	C	6dB	Micro B	8.5dB
10G	8.5dB	C	6dB	C	8.5dB

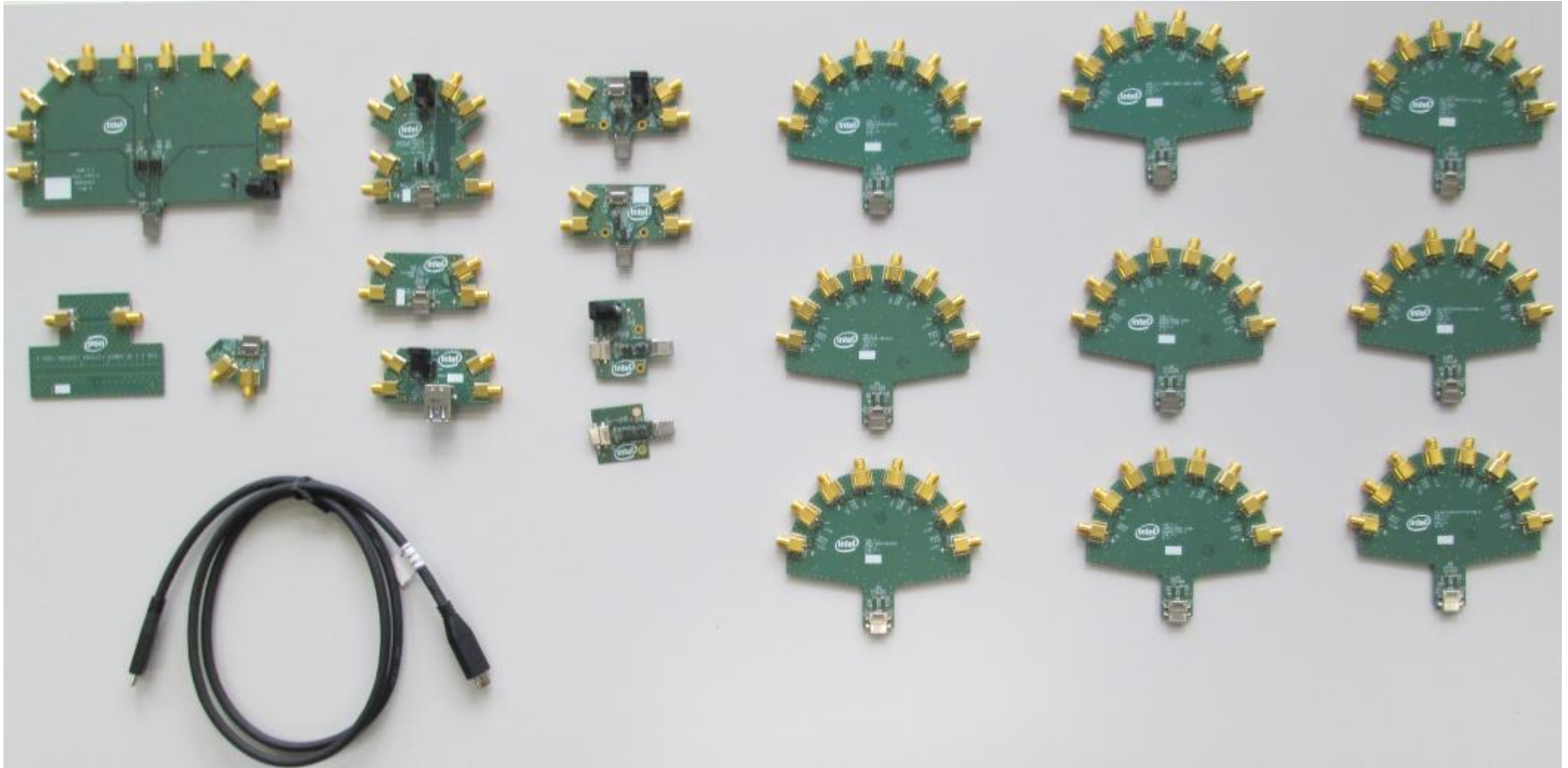




USB 3.1 Type-C TX Test Solutions

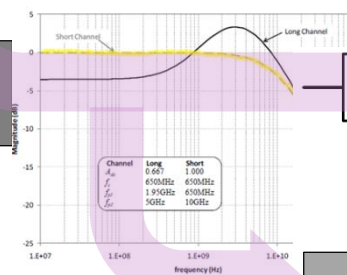
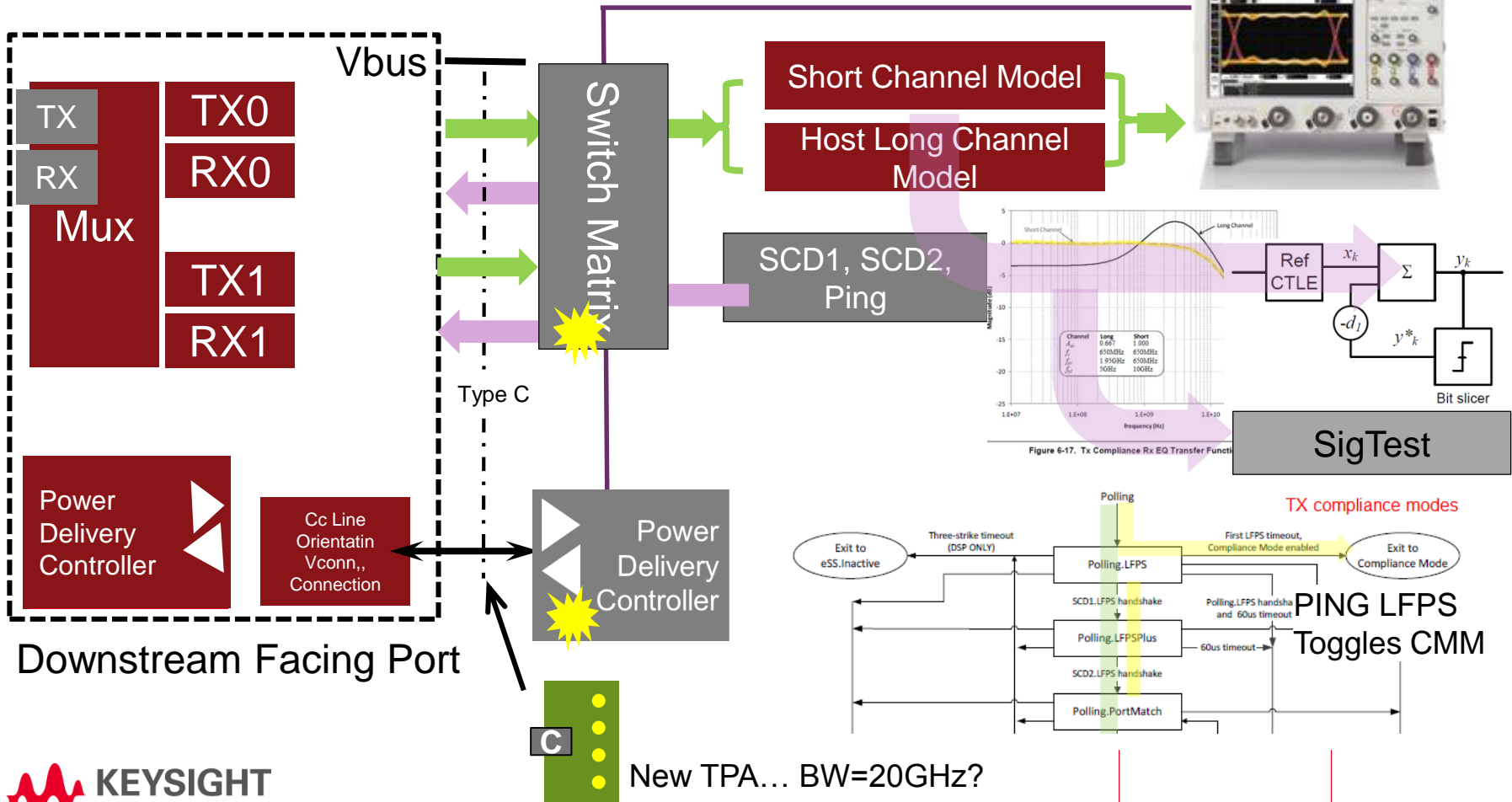
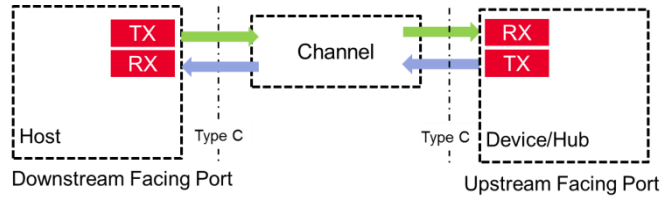
USB 3.1 gen2 10Gb/s

USB 3.1 Type C Fixture Kit rev 2 HW channel

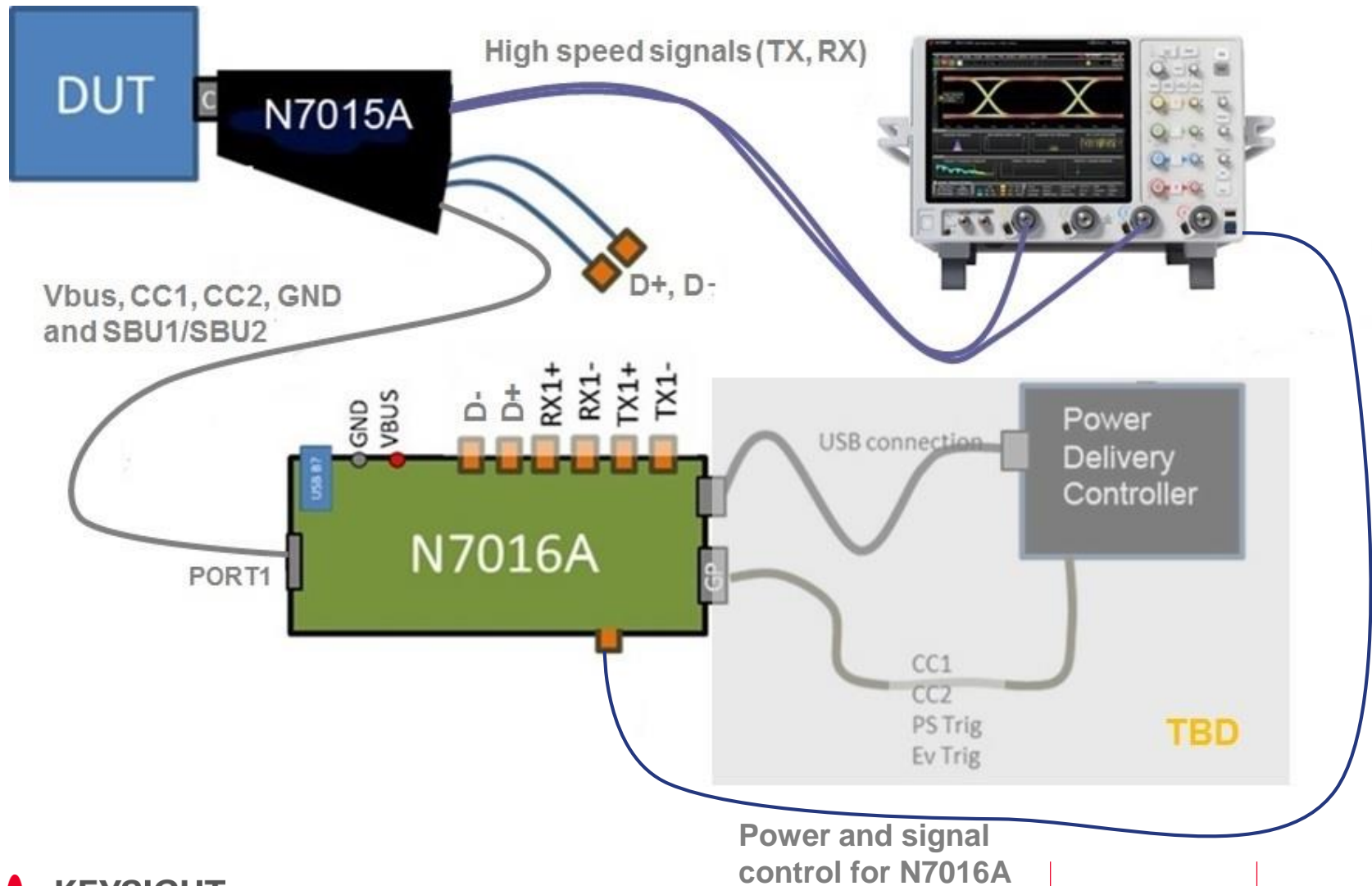


Testing USB 3.1

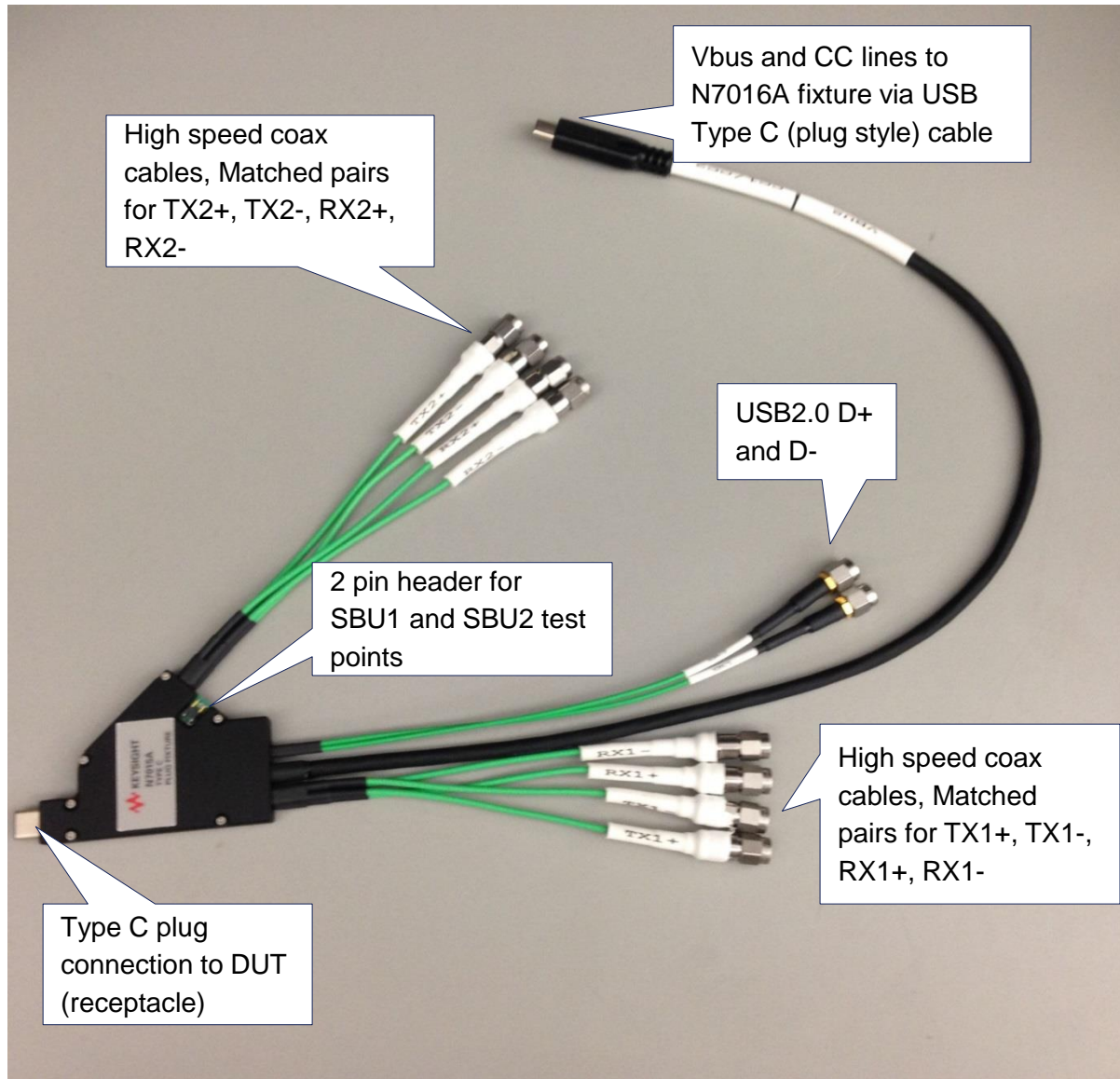
TX w/Type C



High level Test Setup for USB C-Connector



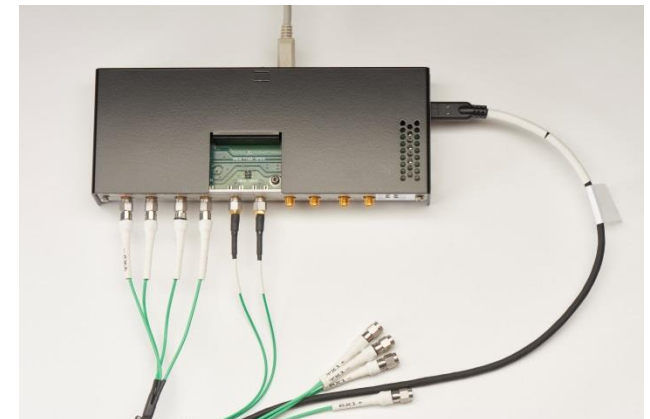
N7015A Type C Test Fixture



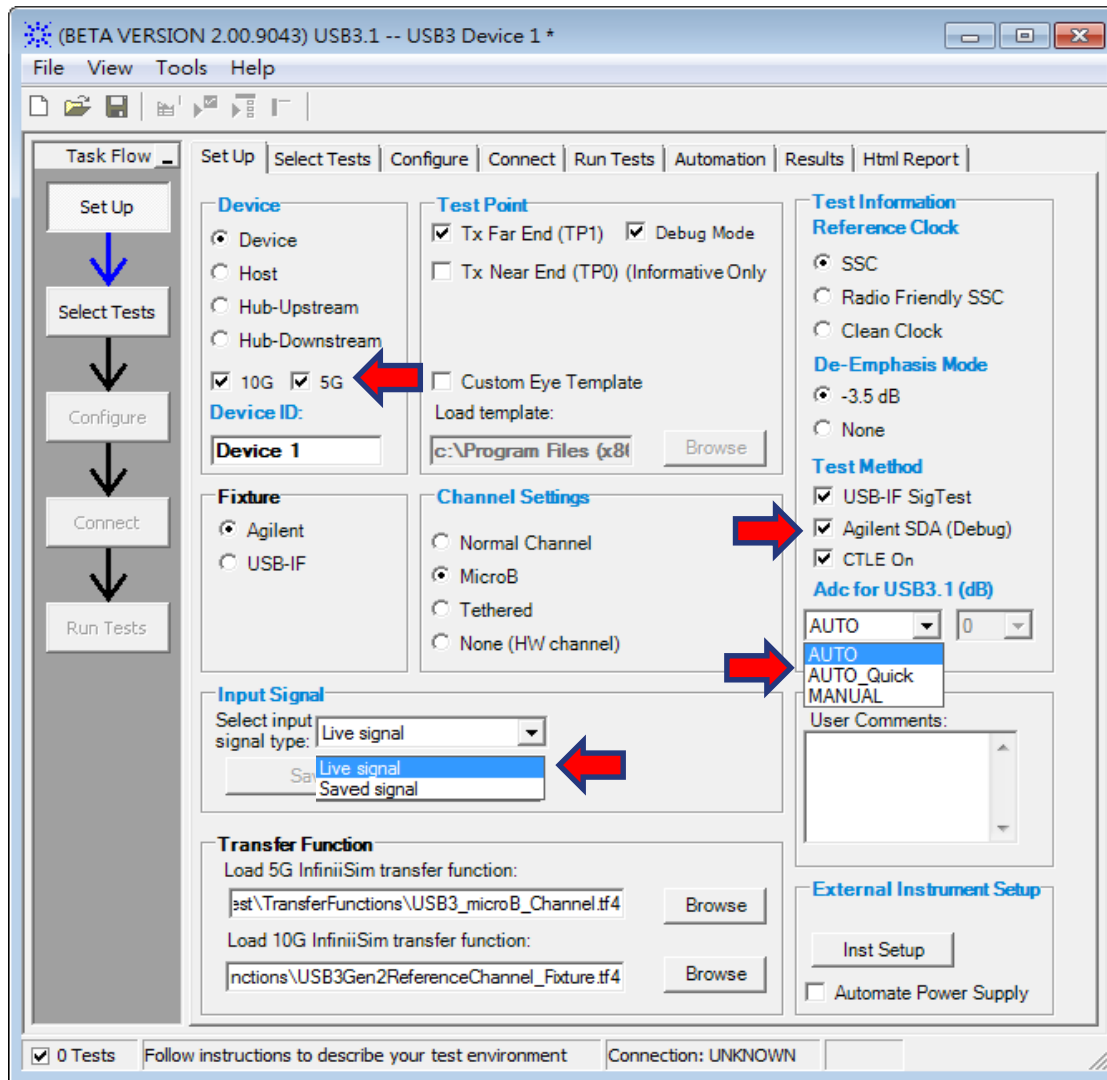
- High speed (TX/RX) and D+/D- lanes to scope through coax cables
- N7015A de-embedding models will be created and integrated in to compliance applications and Infiniium baseline software
- Power and Control signals to low speed N7016A fixture though type C cable
- View SBU1/2 signals

N7016A Type-C low speed signal access and control fixture

- Connects to N7015A through a captive C type cable (port 1) conveying CC_1 , CC_2 , SBU1, SBU2, V_{BUS} and GND
- Controls to terminate CC_1 , CC_2 independently (Ra, Rp, Rd)
- Control to load Vconn (2 different loadings possible)
- External power for power consumers
- Type C receptacle to plug into other devices or cables (port 2)
- USB2.0 interface for external control from application or standalone SW on a PC



U7243B USB 3.1 TX Compliance Application



Keysight solution features:

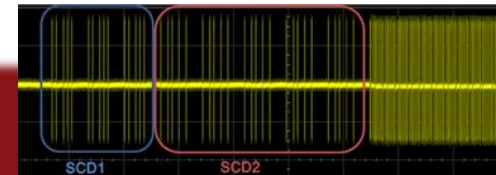
- ✓ Support USB3.1 Gen1/Gen2
- ✓ USB-IF Sigtest & Keysight SDA algorithm
- ✓ CTLE Adc scan
- ✓ Support live & saved waveform
- ✓ USB-IF and customer's embedded transfer function
- ✓ External instrument for triggering SCD1/2, LBPM and toggle Compliance Pattern

U7243B USB 3.1 TX Compliance Application

The screenshot shows the application interface with the following test categories and items:

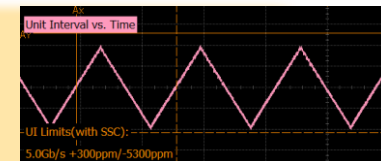
- All USB3 Tests**
 - 5G Test
 - 10G Test
 - 10G Transmitter Low Frequency Periodic Signaling Tests
 - 10G SCD and LBPS Tests
 - 10G LBPS tPWM
 - 10G LBPS tLFPS_0
 - 10G LBPS tLFPS_1
 - 10G SuperSpeedPlus Capability Declaration (SCD1)
 - 10G SuperSpeedPlus Capability Declaration (SCD2)
 - 10G SCD Rise Time
 - 10G SCD Fall Time
 - 10G SCD Duty Cycle
 - 10G SCD Period
 - 10G SCD tRepeat
 - 10G SCD tBurst
 - 10G SCD Differential Voltage
 - 10G SCD Common Mode Voltage
 - 10G Transmitter SSC Tests
 - 10G TSSC-Freq-Dev-Min
 - 10G TSSC-Freq-Dev-Max
 - 10G SSC Modulation Rate
 - 10G SSC df/dt
 - 10G eye measurement test
 - CTLE Adc Selection
 - 10G Transmitter Eye Far End (TP1) Tests (Agilent SDA)(CTLE On)
 - 10G Far End Template Test (SDA)(CTLE ON)
 - 10G Far End Differential Output Voltage (SDA)(CTLE ON)
 - 10G Far End Random Jitter (SDA)(CTLE ON)
 - 10G Far End Maximum Deterministic Jitter (SDA)(CTLE ON)
 - 10G Far End Total Jitter at BER-12 (SDA)(CTLE ON)
 - 10G Transmitter Eye Far End (TP1) Tests (USB-IF SigTest)(CTLE On)
 - 10G Far End Random Jitter (CTLE ON)
 - 10G Far End Maximum Deterministic Jitter (CTLE ON)
 - 10G Far End Total Jitter at BER-12 (CTLE ON)
 - 10G Far End Template Test (CTLE ON)
 - 10G Far End Differential Output Voltage (CTLE ON)

Gen 1 test items, LFPS, SSC, eye mask, Jitter



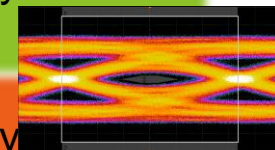
Gen2 LFPS, tRepeat, tBurst, tPWM, tLFPS_0, tLFPS_1

SSC test items



Select/Scan for optimal Adc of CTLE

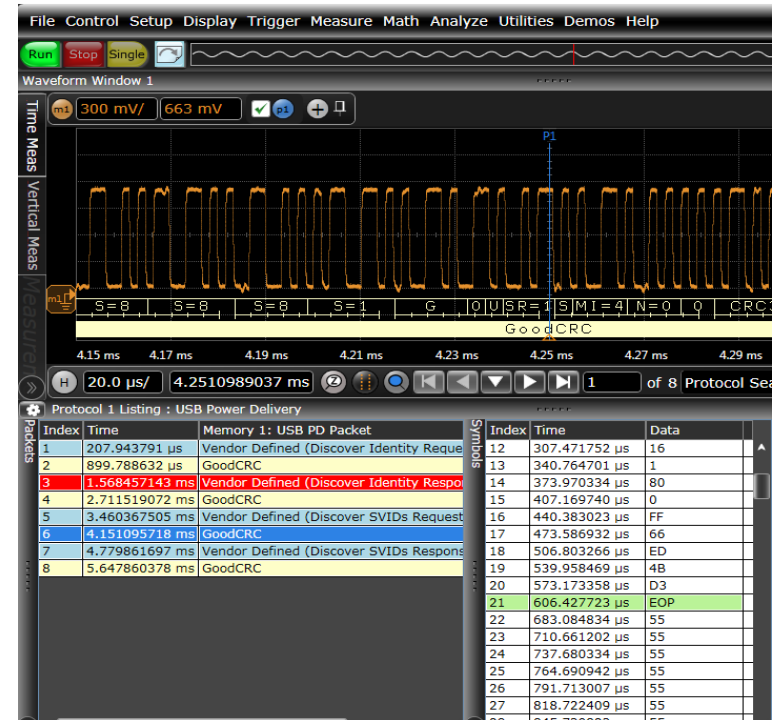
Eye mask and Jitter test by SDA algorithm



Eye mask and Jitter test by SigTest algorithm

N8821A/B USB 3.1 Gen1/Gen2 Protocol Trigger and Decode

- USB 3.1 Gen1 and Gen 2 protocol decode in less than 30 seconds
- Integrated software-based protocol-level triggers
- Save time and eliminate errors by viewing packets at the protocol level
- Use time-correlated views to quickly troubleshoot serial protocol problems back to their timing or signal integrity root cause





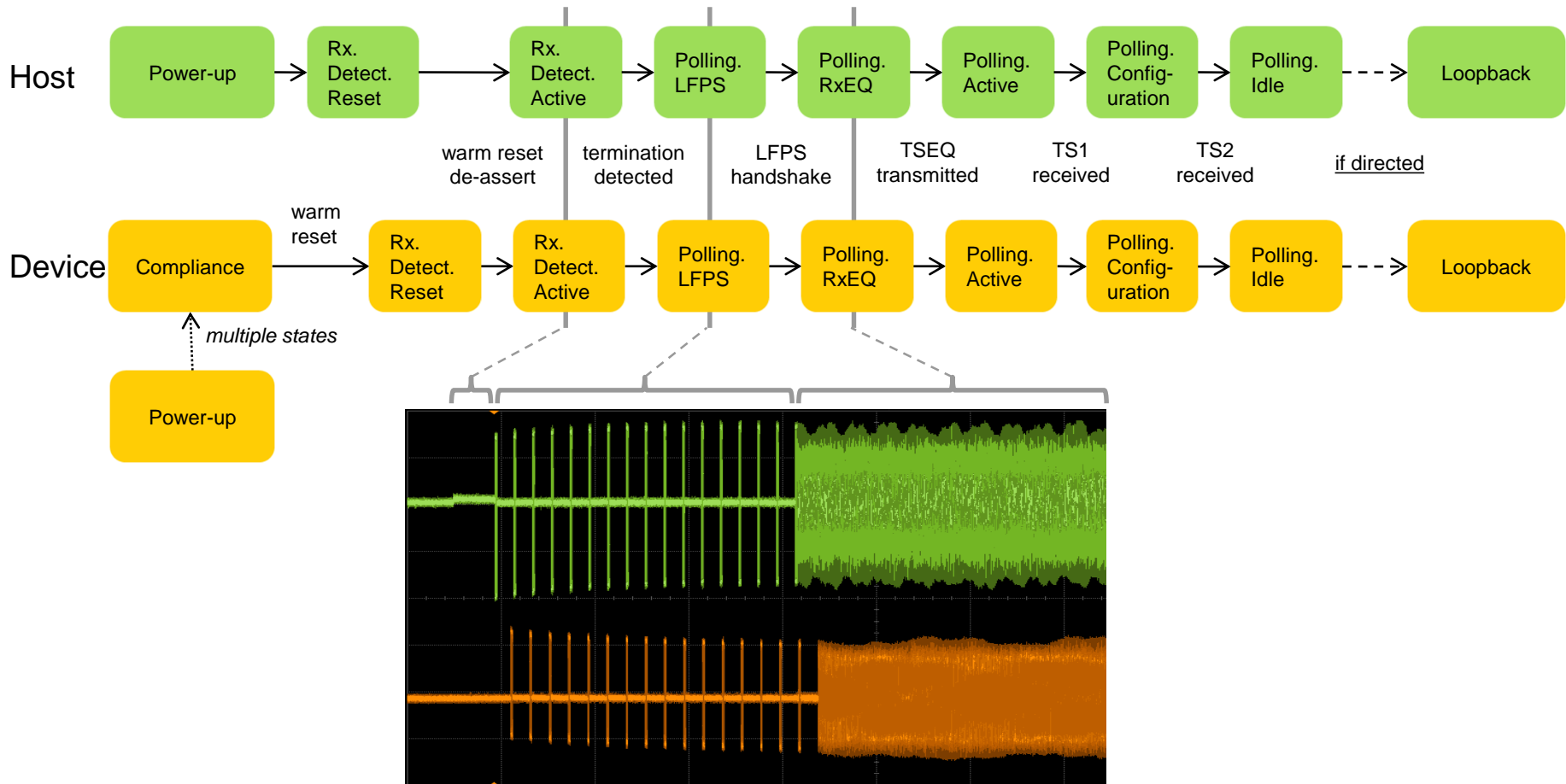
USB 3.1 Type-C RX Test Solutions

USB 3.x Comparison

	USB 3.0 (aka USB 3.1 Gen 1 PHY)	USB 3.1 (aka USB 3.1 Gen 2 PHY)
Data rate	5Gb/s \pm 300ppm (SSC variations not accounted for)	10Gb/s \pm 300ppm (SSC variations not accounted for)
Coding	<ul style="list-style-type: none"> • 8b/10b • scrambler: $G(X) = X^{16} + X^5 + X^4 + X^3 + 1$ scrambler reset by COM (K28.5) or BRST seed: FFFFh • Symbol lock: K28.5, some implementations might be able to use K28.1 or K28.7 	<ul style="list-style-type: none"> • 128b/132b • scrambler: $G(X) = X^{23} + X^{21} + X^{16} + X^8 + X^5 + X^2 + 1$ scrambler reset by SYNC OS seed: 1D BFBCh • Block alignment: SYNC OS + SDS OS and realignment through SKP OS
SKP	K28.1, K28.1	SKP OS with variable number of SKPs
LFPS		Device host capability negotiation is done during Low Frequency Periodic Signaling (LFPS) phase using LFPS modulation schemes
CDR	PLL transfer: <ul style="list-style-type: none"> • $f_{3dB} = 10\text{MHz}$ • $\text{peaking}_{max} = 2\text{dB}$ HPF transfer: <ul style="list-style-type: none"> • $f_{3dB} = 4.9\text{MHz}$ • $\text{peaking} \approx 0\text{dB}$ • $\text{damping factor} = 0.707$ 	PLL transfer: <ul style="list-style-type: none"> • $f_{3dB} = 15\text{MHz}$ • $\text{peaking}_{max} = 2\text{dB}$ HPF transfer: <ul style="list-style-type: none"> • $f_{3dB} = 7.5\text{MHz}$ • $\text{peaking} \approx 0\text{dB}$ • $\text{damping factor} = 0.707$
SSC	<ul style="list-style-type: none"> • Modulation rate: 30kHz to 33kHz • Deviation: +0 to -4000(min)/-5000(max) • Max slew rate: 10ms/s 	<ul style="list-style-type: none"> • Modulation rate: 30kHz to 33kHz • Deviation: +0 to -4000(min)/-5000(max) • New df/dt requirement: 1250 (max) ppm/μs instead of max slew rate spec
De-emphasis	Post: -3dB	Pre: 2.2dB Post: -3.1dB

Typical USB 3.0 Link Turn-on Sequence

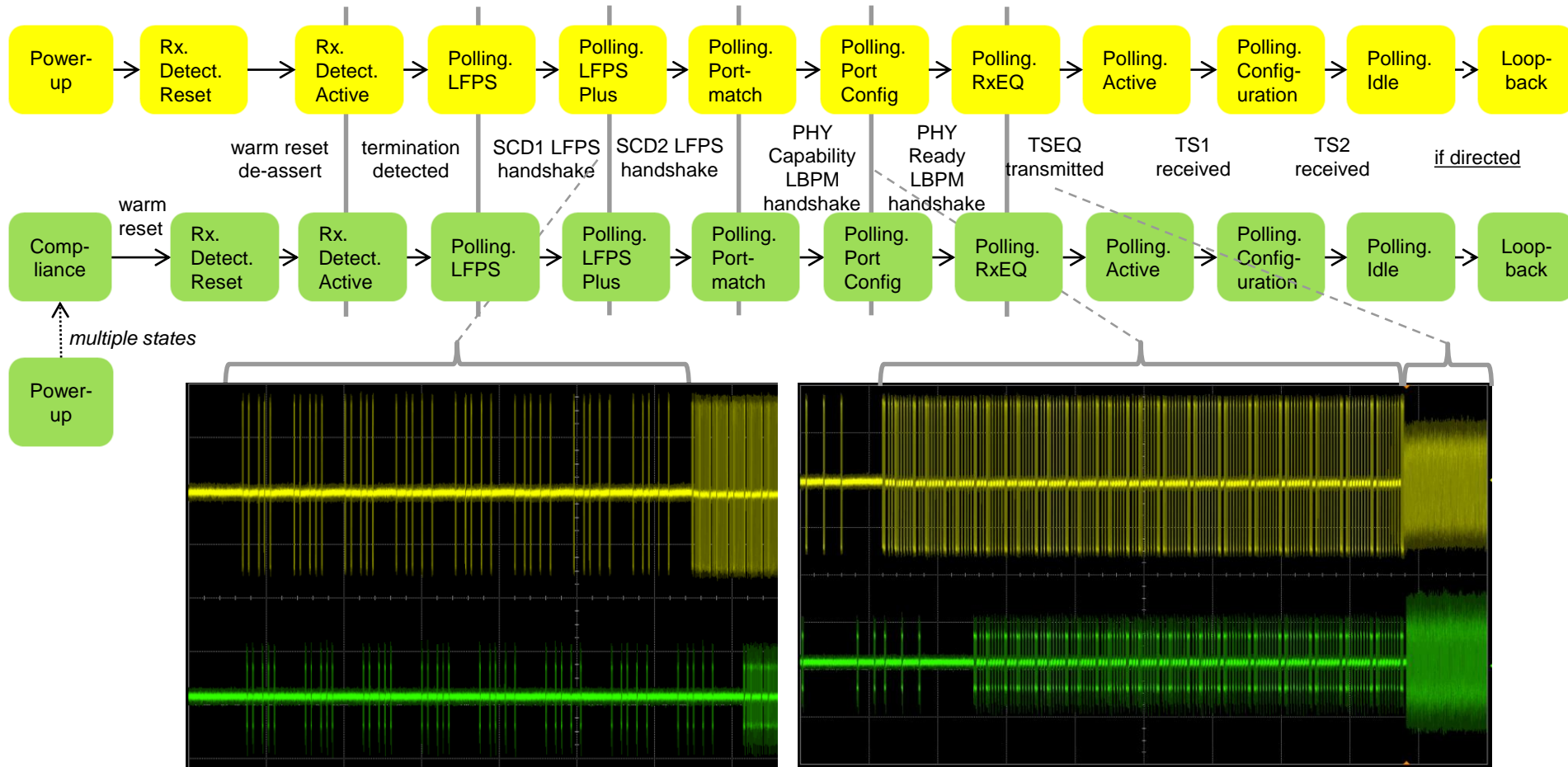
LTSSM states:



J-BERT's sequence trigger can be used to trigger scope captures for each training step → in combination with scope's protocol decode very helpful for debugging a training sequence

Typical USB 3.1 Link Turn-on Sequence

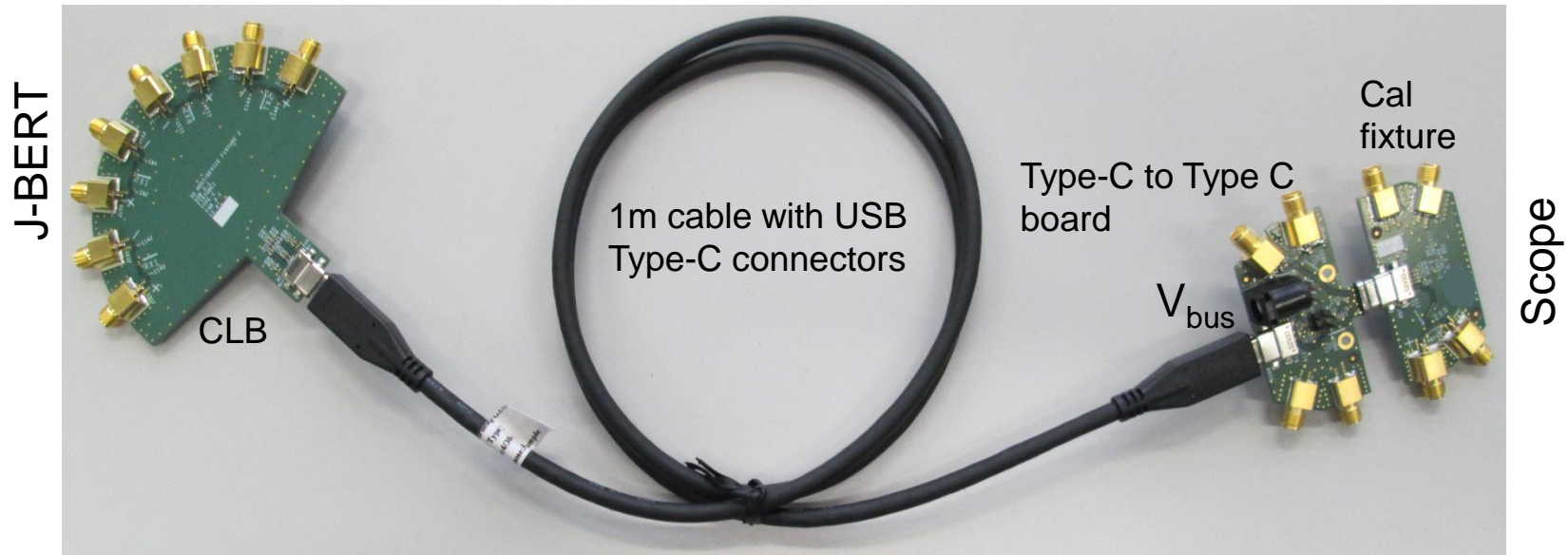
LTSSM states:



J-BERT's sequence trigger can be used to trigger scope captures for each training step → very helpful for debugging a training sequence

USB 3.0/3.1 5Gb/s RX Test Calibration

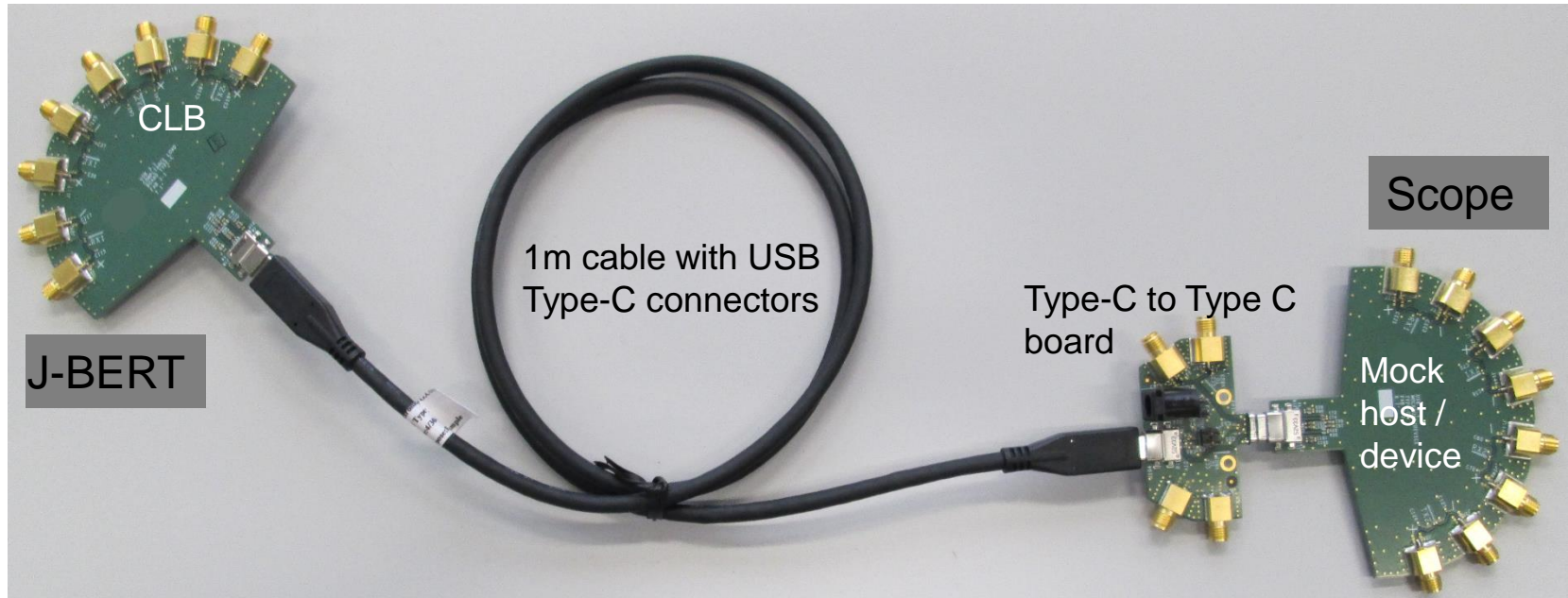
Compliance Test Channel – Type-C Connector



- Same setup for host or device with exception of Type-C to Type-C board:
 - Host RX – breakout for DUT TX to BERT RX channel, no V_{bus} connection
 - Host TX – no breakout, no V_{bus} connection
 - Device RX – breakout for DUT TX to BERT RX, V_{bus} connection
 - Device TX – no breakout, no V_{bus} connection
- Exact trace length of CLB is not defined yet
- 1m cable with USB Type-C connectors

USB 3.1 gen2 10Gb/s

USB 3.1 Type C 23dB Cal Channel



Compliance Load Board (CLB):

- A fixture set contains three CLBs with traces of different lengths to be able to adjust residual ISI

Four versions of Type-C to Type-C board:

- Host RX – breakout for DUT TX to BERT RX channel, no V_{bus} connection
- Host TX – no breakout, no V_{bus} connection
- Device RX – breakout for DUT TX to BERT RX, V_{bus} connection
- Device TX – no breakout, no V_{bus} connection

Mock-Up fixture:

- Simulates reference device/host loss. Used for calibration only.

USB 3.1 gen2 10Gb/s

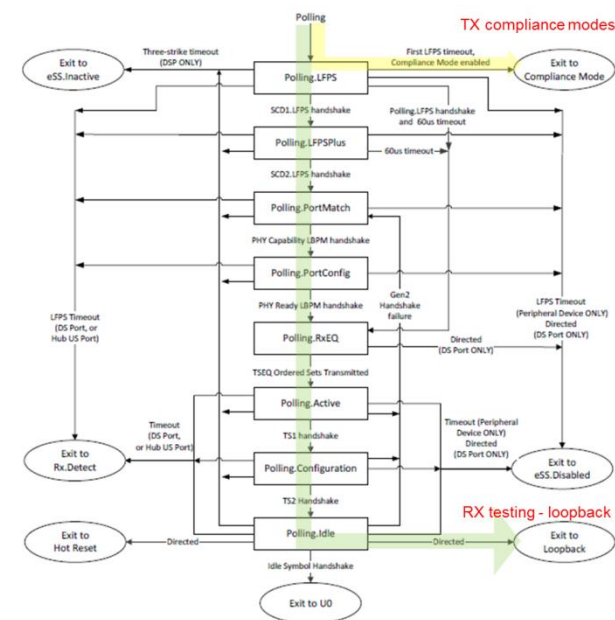
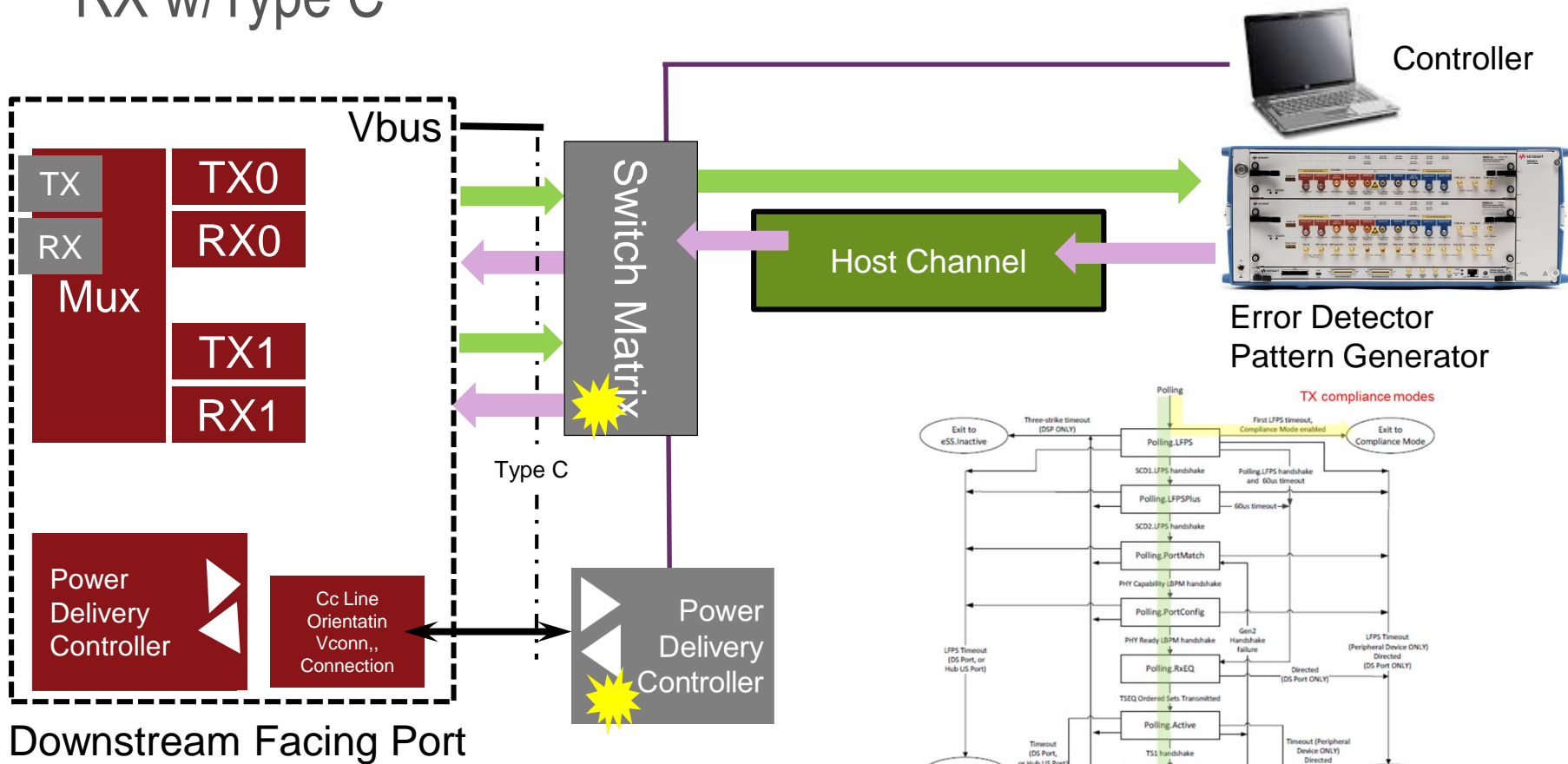
USB 3.1 Type C 14.5dB Test Channel



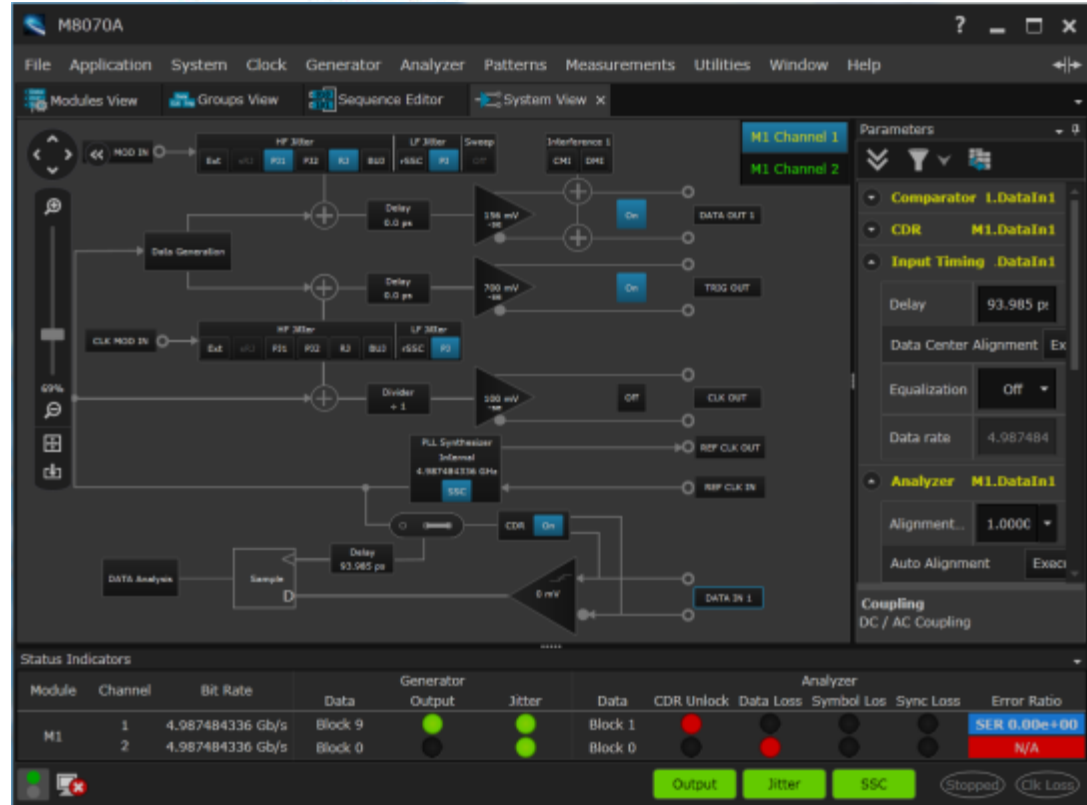
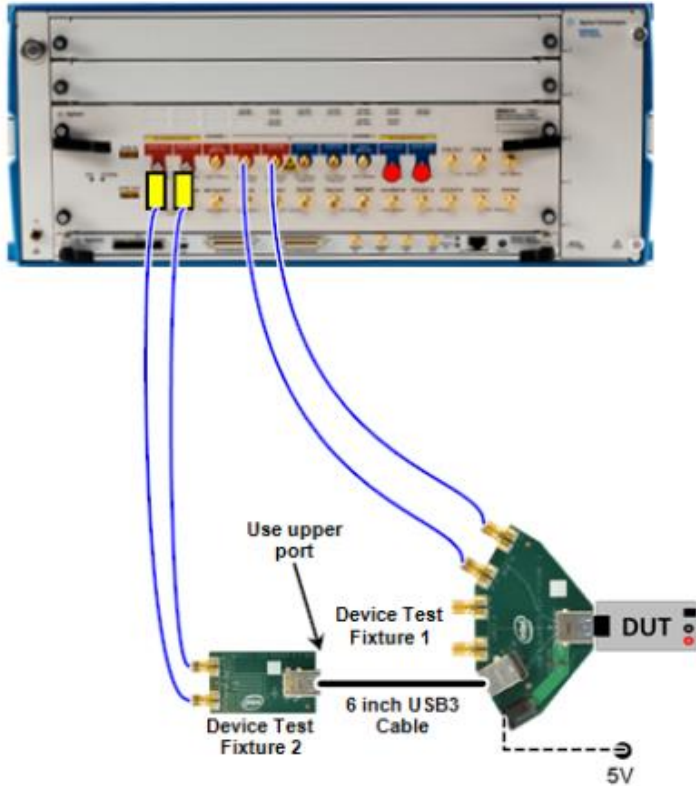
Unlike for USB 3.0/3.1 gen1 5G RX testing USB 3.1 gen2 10G RX compliance testing requires to test each test frequency for 10^{12} bits.

Testing USB 3.1

RX w/Type C



USB 3.1 Gen1/Gen2 Receiver Test Setup



Key capabilities:

- Analysis of coded & retimed data
- Support of **8b/10b** and **128b/132b HW** coding and decoding as well as HW scrambling
- Generates calibrated stress conditions for RX test (SSC, SJ, RJ, De-emphasis, ISI)
- **Emulate LFPS 3-level signals** with built-in electrical idle for loopback training and via channel
- **Integrated Link Training, Tx Eq, Noise Impairment, Variable ISI, Receiver Equalizer/Eye Opener**

N5990A Test Automation for USB

Test Overview

Compliance Tests:

- 5G RX Compliance long channel
- 5G RX Compliance short channel
- 5G RX Compliance LFPS
- 10G RX Compliance position 1
- 10G RX Compliance position 2

Characterization Tests:

- RX constant parameter
- RX jitter tolerance (SJ margin)
- RX and LFPS sensitivity
- RX data rate deviation
- LFPS Duty Cycle

The screenshot displays the N5990A Test Automation Software Platform interface. The main window is titled "N5990A Test Automation Software Platform" and features a menu bar (File, Station, Sequencer, Help) and a toolbar with icons for Configure DUT, Load, Save, Start, Abort, Pause, Print, Properties, and Log List. The interface is divided into several sections:

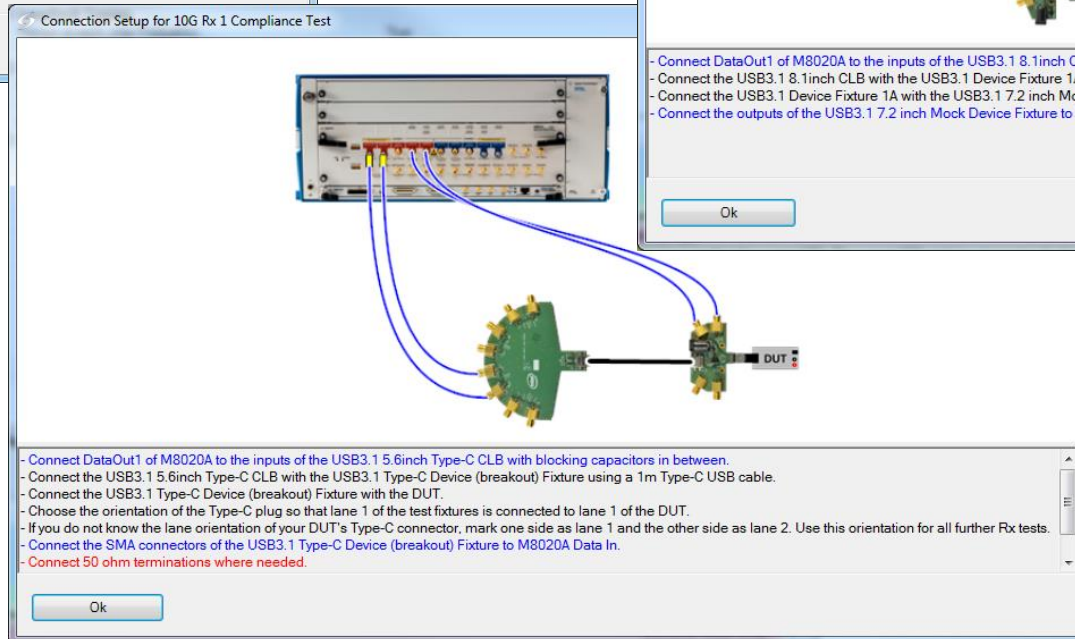
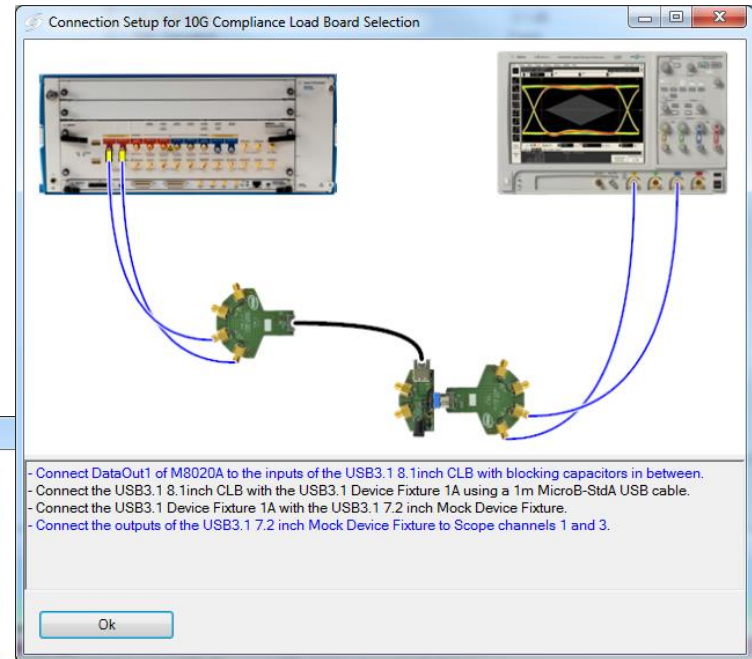
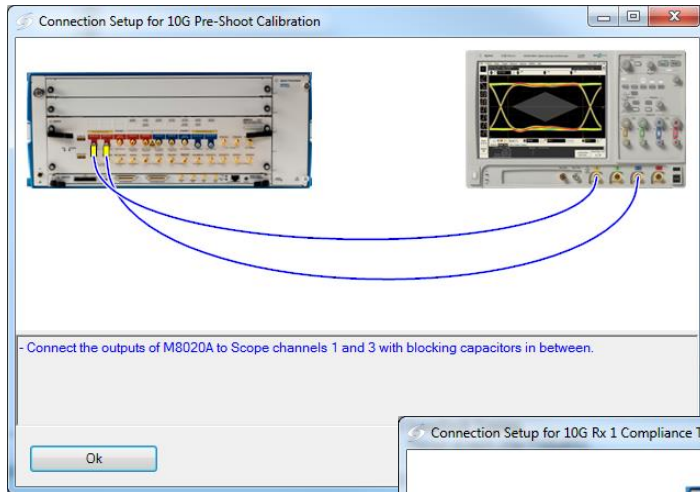
- Test Tree (Left):** A hierarchical tree view showing test categories and individual tests. The "Receiver" section is expanded, showing tests like "10G Compliance Eye Verification", "Super Speed", "5G Rx Compliance Test", "5G Rx Constant Parameter Stress Test", "5G Rx Jitter Tolerance Test", "5G Rx Sensitivity Test", "5G Rx Data Rate Deviation Test", "Short Channel Tests", "5G Rx Short Channel Compliance Test", "5G Rx Short Channel Constant Parameter Stress Test", "5G Rx Short Channel Jitter Tolerance Test", "5G Rx Short Channel Sensitivity Test", "5G Rx Short Channel Data Rate Deviation Test", "LFPS Tests", "5G Rx LFPS Compliance Test", "5G Rx LFPS Sensitivity Test", "5G Rx Receiver LFPS Duty Cycle Test", "Super Speed Plus", "Rx 1", "Rx 2", and "Transmitter". The "10G Rx 2 Constant Parameter Stress Test" is highlighted in blue.
- Configuration Panel (Right):** A table-like view showing test parameters and their values. The "BER" section is expanded, showing parameters like "BER Test Duration" (120 s), "Allowed Errors" (1), and "Relax time for BER Measurement" (5 s). Other sections include "Loopback Training", "Sequencer", "Specification", and "Repetitions".
- Log List (Bottom):** A table showing the progress of test steps. The log entries are as follows:

Severity	Message	Date
Progress	10G Rx 2 Jitter Tolerance Test: Step 1 - Jitter Frequency = 1 MHz	1/29/2016 1:15:38 PM
Progress	10G Rx 2 Jitter Tolerance Test: Step 2 - Jitter Frequency = 2 MHz	1/29/2016 1:16:40 PM
Progress	10G Rx 2 Jitter Tolerance Test: Step 3 - Jitter Frequency = 4 MHz	1/29/2016 1:17:20 PM
Progress	10G Rx 2 Jitter Tolerance Test: Step 4 - Jitter Frequency = 7.5 MHz	1/29/2016 1:17:52 PM
Progress	10G Rx 2 Jitter Tolerance Test: Step 5 - Jitter Frequency = 50 MHz	1/29/2016 1:18:36 PM
Progress	10G Rx 2 Jitter Tolerance Test: Step 6 - Jitter Frequency = 100 MHz	1/29/2016 1:19:21 PM

At the bottom of the interface, a status bar indicates "Performing procedure step 6 of iteration 0, total step count is 6" and "Running Online" with "USB Station" selected.

N5990A Test Automation for USB 3.0/3.1

Ease of Use



The N5990A Test Automation for USB 3.0/3.1 guides users through every setup changes with connection diagrams and detailed descriptions

Receiver Jitter Tolerance curve

Gen1 vs Gen2

- Rx Jtol RJ & Tx EQ updated by ECN
- Gen 2 define 7 SJ points in spec.
- Gen 1 define 5 SJ points in Spec, but 8 points in CTS

Symbol	Parameter	Gen 1	Gen 2	Units
f1	Tolerance corner	4.9	7.5	MHz
J _{Rj}	Random Jitter	0.0121	0.0100	UI rms
J _{Rj_p-p}	Random Jitter peak- peak at 10 ⁻¹²	0.17	0.141	UI p-p
J _{Pj_500kHz}	Sinusoidal Jitter	2	2.56	UI p-p
J _{Pj_1MHz}		1	1.28	UI p-p
J _{Pj_2MHz}		0.5	0.64	UI p-p
J _{Pj_4MHz}		N/A	0.32	UI p-p
J _{Pj_f1}		0.2	0.17	UI p-p
J _{Pj_50MHz}		0.2	0.17	UI p-p
J _{Pj_100MHz}		N/A	0.17	UI p-p
V _{full_swing}		Transition bit differential voltage swing	0.75	TBD
V _{EQ_level}	Non transition bit voltage (equalization)	-3	Pre=2.2 Post= -3.1	dB

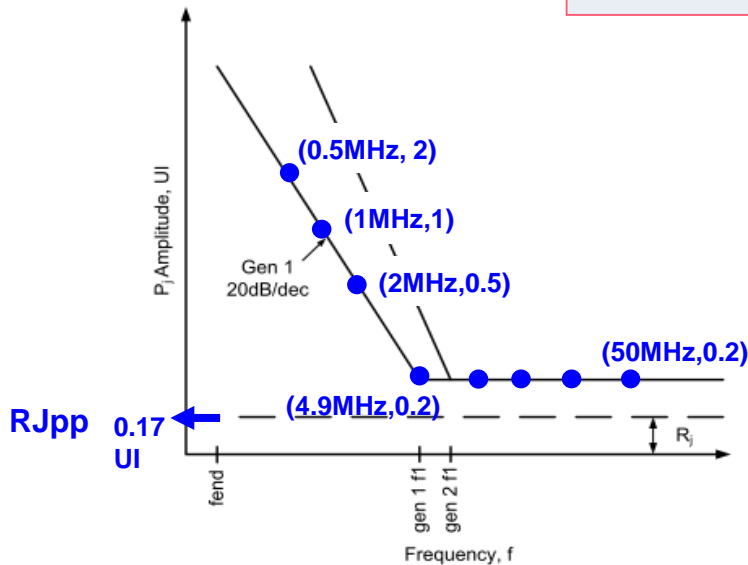


Figure 6-28. Jitter Tolerance Curve

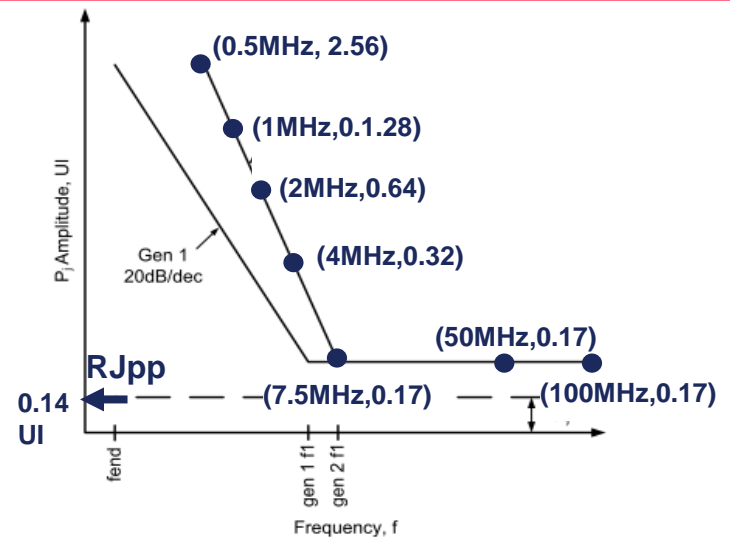
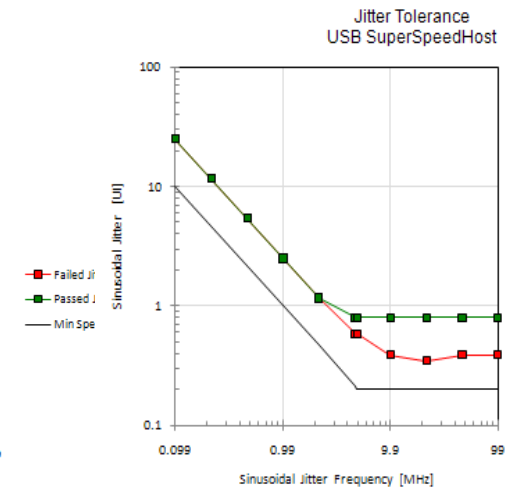
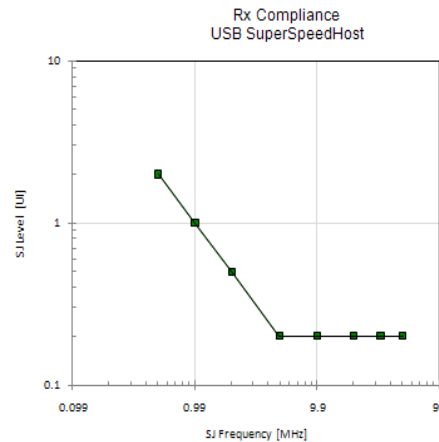


Figure 6-28. Jitter Tolerance Curve

SuperSpeed Receiver Tests

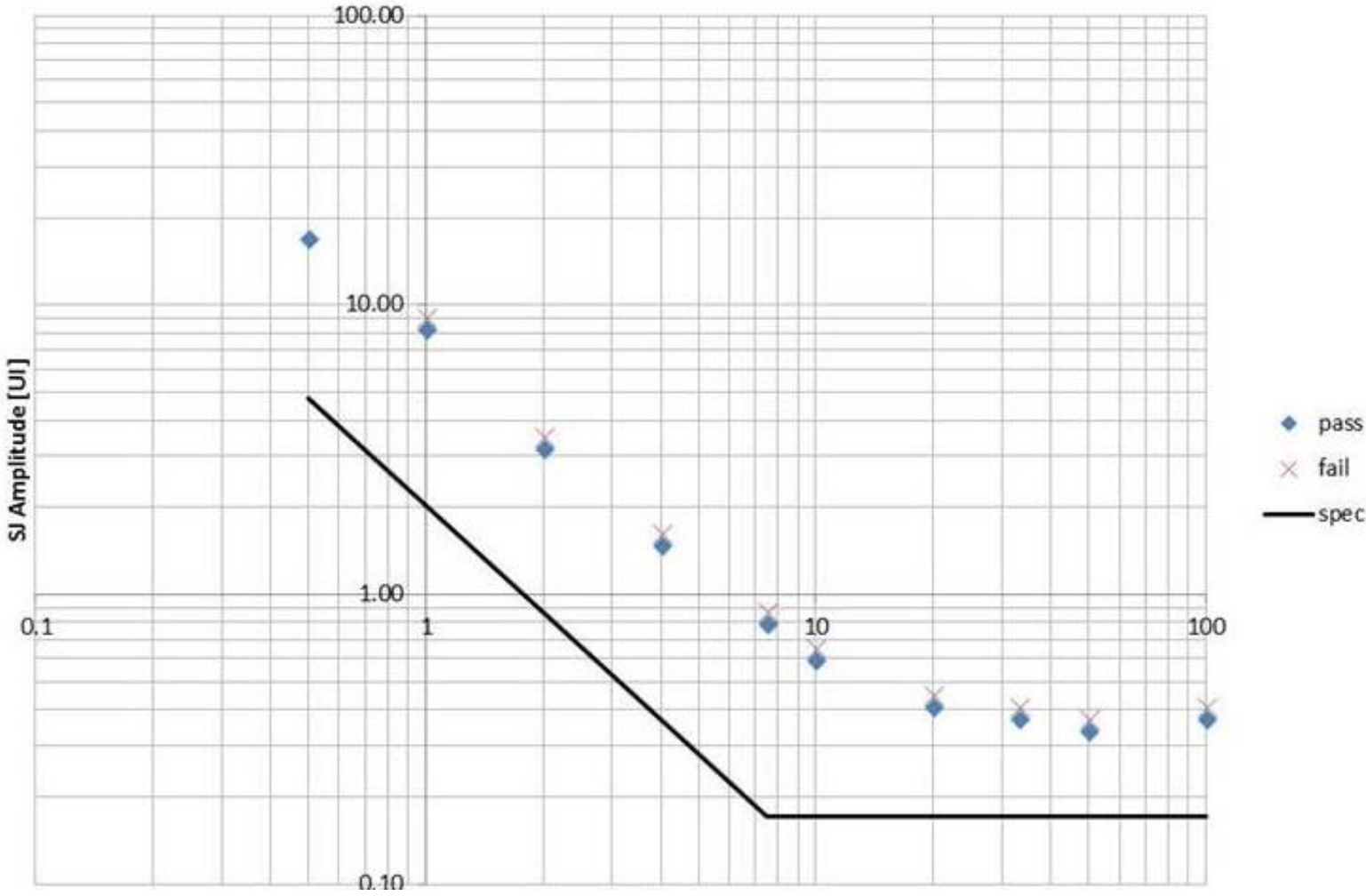
Rx Compliance and Jitter Tolerance Testing

- Automated instrument control for:
 - Setup calibration
 - Compliance test
 - Characterization test
 - Support for debugging
- Operator guidance
- Sophisticated test reports
- Controls J-BERT, Oscilloscope.
- Supports full product characterization including transmitter measurements



Result	SJ Frequency [MHz]	Failed Jitter [UI]	Passed Jitter [UI]	Min Spec [UI]	Symbol Errors
pass	0.500		2.00	2.000	0
pass	1.000		1.00	1.000	0
pass	2.000		0.50	0.500	0
pass	4.300		0.20	0.200	0
pass	10.000		0.20	0.200	0
pass	20.000		0.20	0.200	0
pass	33.000		0.20	0.200	0
pass	50.000		0.20	0.200	0

JTOL Margining Test Results



Receiver Characterization Example

The screenshot displays the N5990A Test Automation Software Platform interface on the left, showing a tree view of test configurations for a USB3 SuperSpeed Device. The 'Receiver' section is expanded, showing various calibration and test steps. On the right, a Microsoft Excel spreadsheet titled 'Jitter Tolerance' is open, featuring a line graph and a data table.

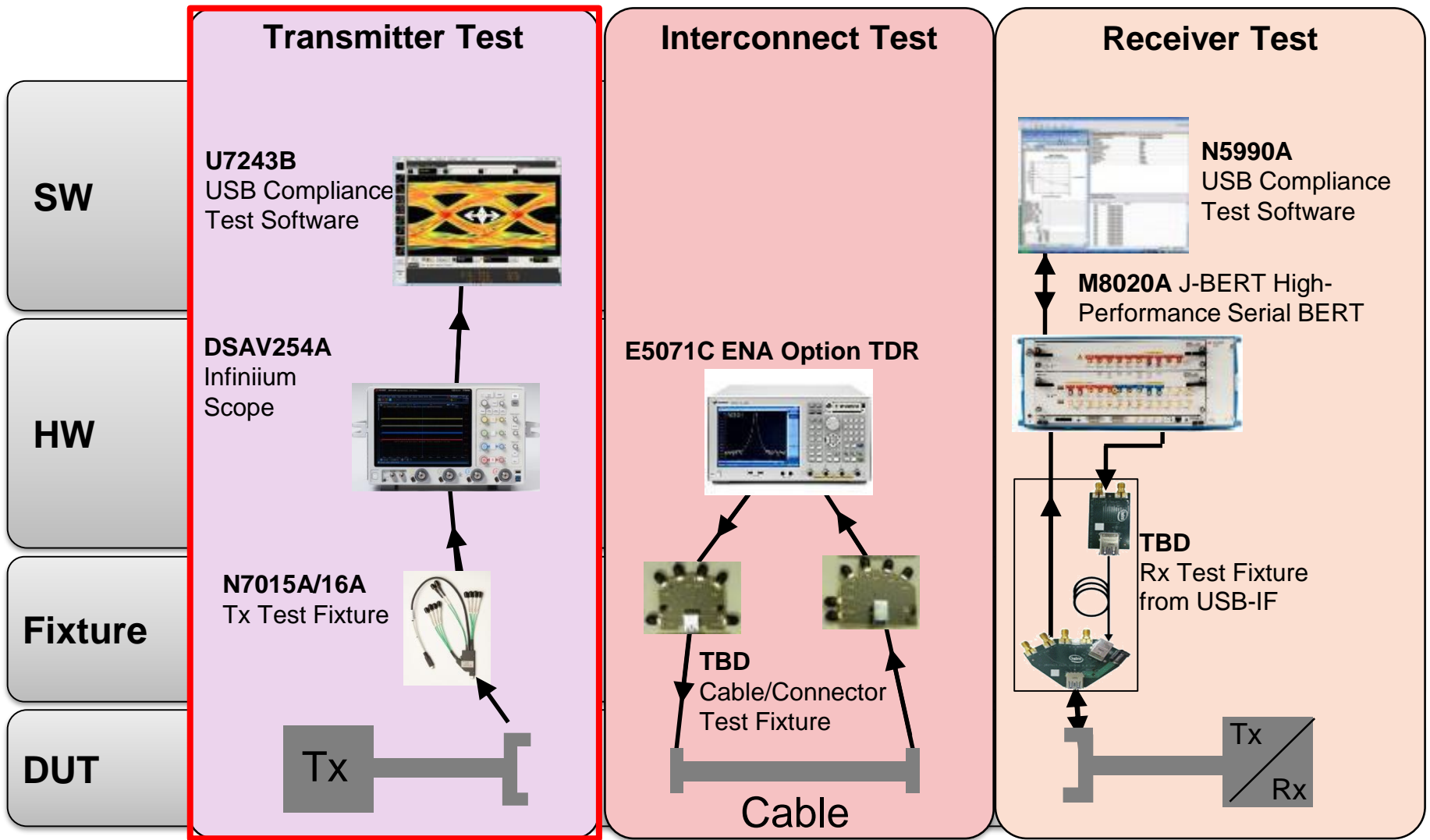
Jitter Tolerance Graph: The graph plots Sinusoidal Jitter [UI] on the y-axis (log scale, 0.1 to 10) against Sinusoidal Jitter Frequency [MHz] on the x-axis (log scale, 0.1 to 100). The legend includes: Min Failed Jitter (red squares), Max Passed Jitter (green squares), Jitter Capability Test Setup (blue line), and Min Spec (black line).

Jitter Tolerance Test Results Table:

Result	Sinusoidal Jitter Frequency [MHz]	Min Failed Jitter [UI]	Max Passed Jitter [UI]	Jitter Test Setup [UI]	Min Spec [UI]	Margin [%]
pass	0.500	4.30	4.30	4.30	2.00	145.8
pass	1.000	2.43	2.43	2.43	1.00	146.8
pass	2.000	1.24	1.24	1.24	0.50	148.8
pass	4.300	0.60	0.64	0.60	0.20	220.0
pass	10.000	0.40	0.44	0.40	0.20	120.0
pass	20.000	0.44	0.40	0.60	0.20	100.0
pass	33.000	0.40	0.44	0.60	0.20	120.0
pass	50.000	0.40	0.44	0.60	0.20	120.0

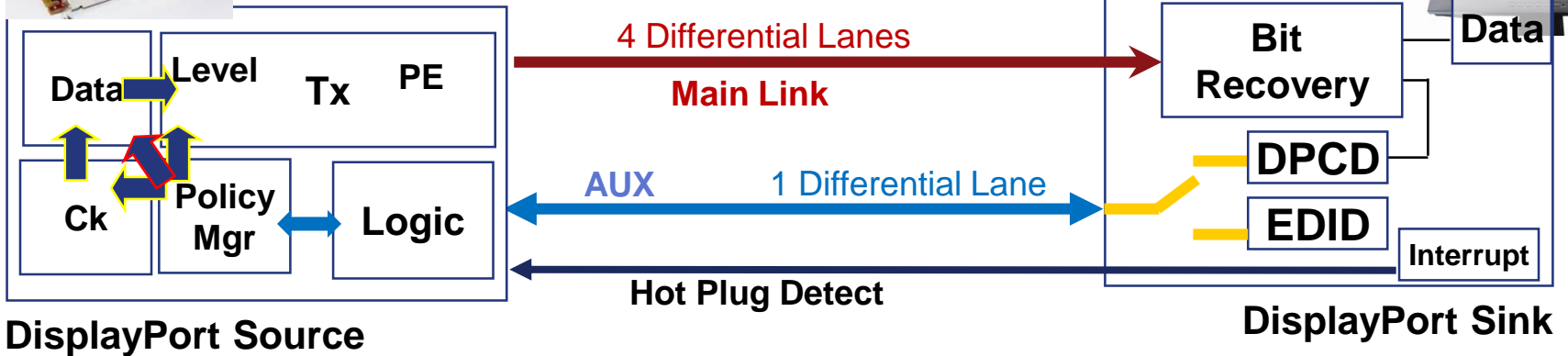
- Automated instrument control for:
 - Setup calibration
 - Compliance test
 - Characterization test
 - Support for debugging
- Operator guidance
- Sophisticated test reports
- Controls J-BERT, Oscilloscope.
- Supports full product characterization including transmitter measurements

Keysight USB 3.1 Total Test Solution



USB Type-C Interface and DP Alt Mode Overview

Review of DisplayPort Interface



Main Link

Up to 4 differential lanes: 4 possible bit rates

TX:

- 4 possible level settings
- 4 possible pre-emphasis settings
- Spread Spectrum Clocking (optional)
- Dual Mode optional

RX:

- Receiver individual clock recovery
- Receiver Tolerance curve specified.
- Receiver Sensitivity = 50mV

AUX Channel

Phy Layer

Bit rate at 1Mbps

Manchester II encoded

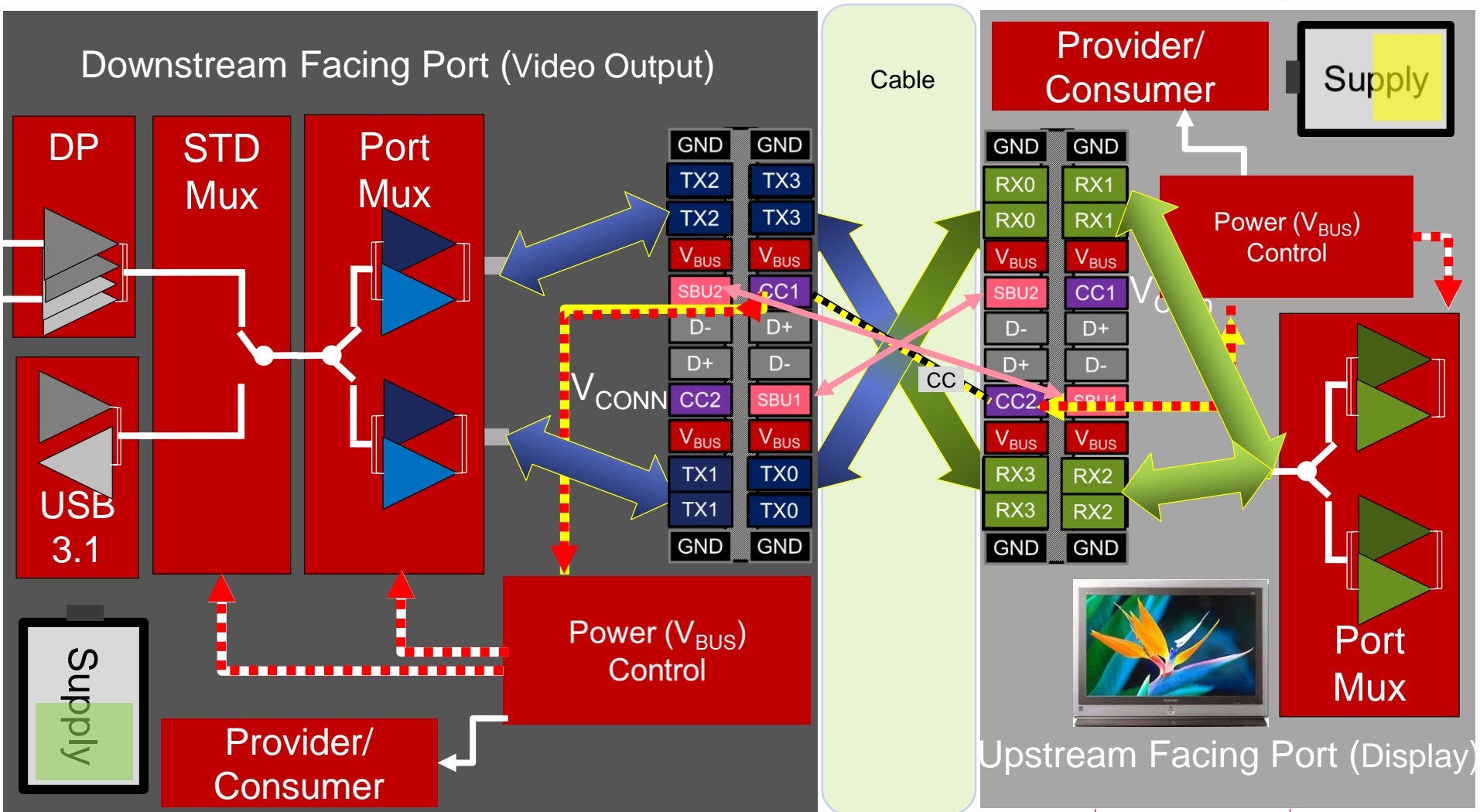
Purpose

Link Management

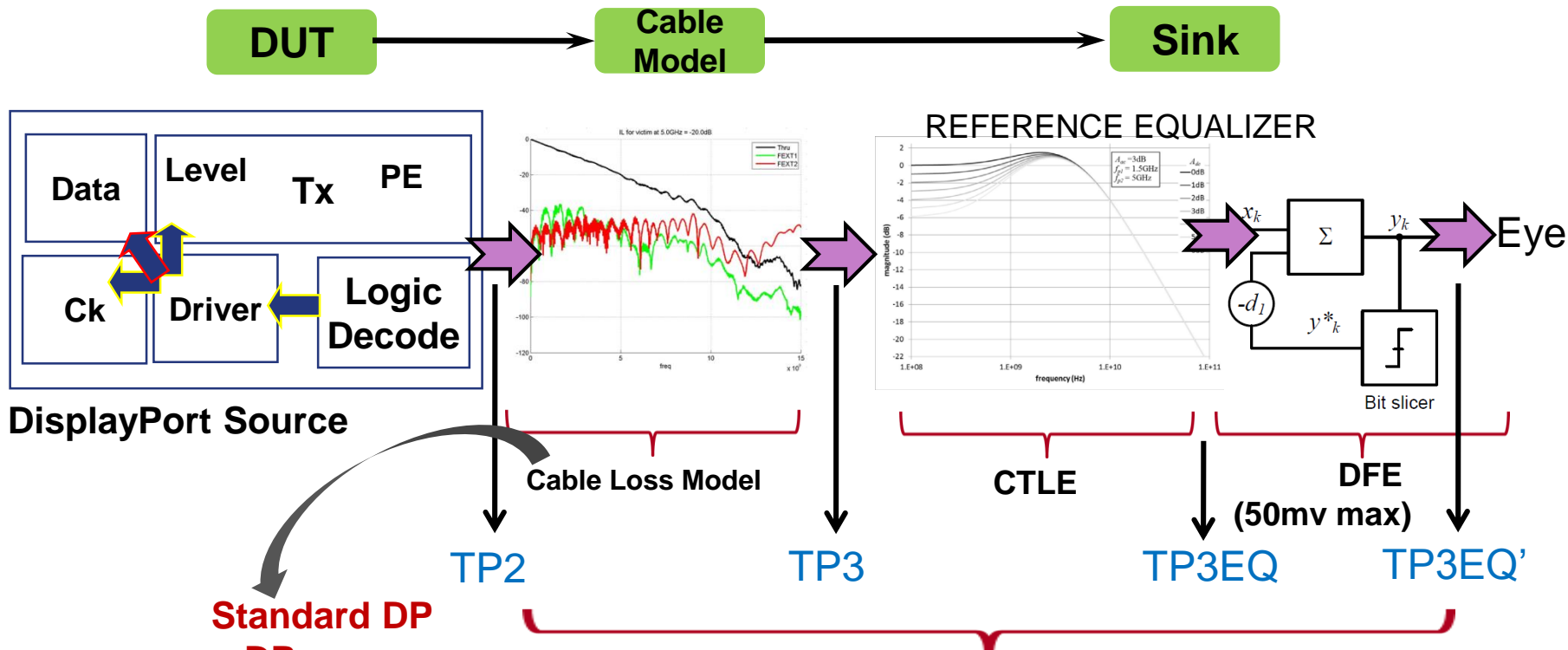
Test Mode control

USB Type C Port Function

Alternate Mode: DisplayPort



DP Transmitter Testing: Whole Channel

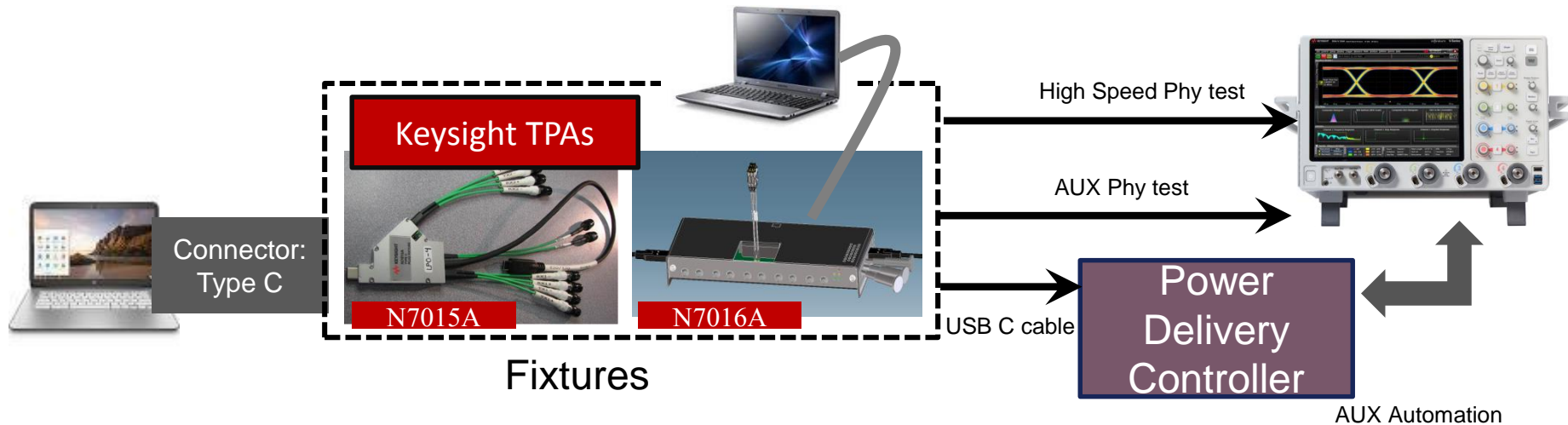
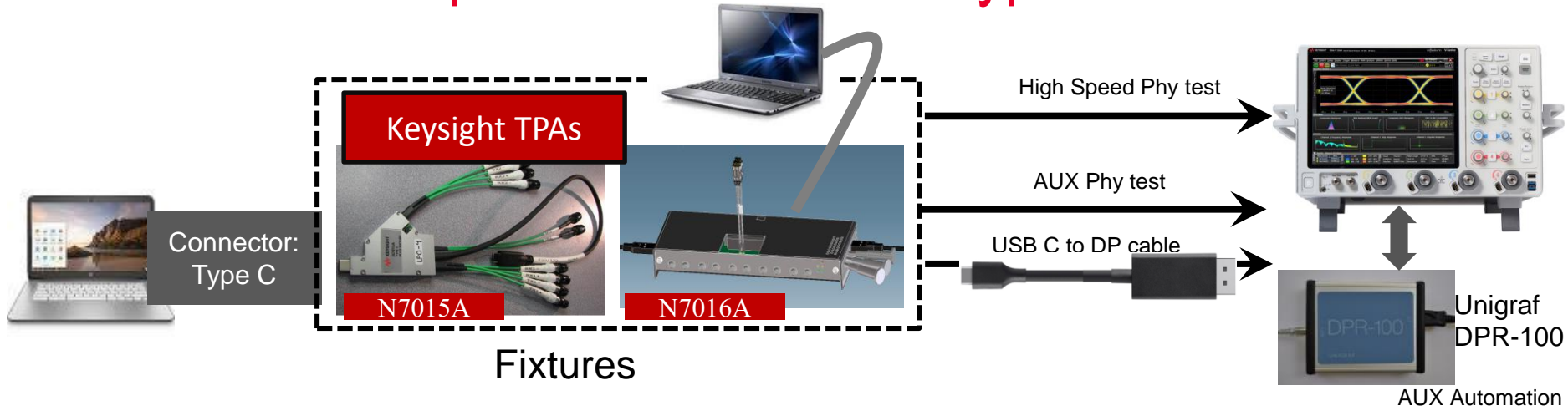


Standard DP
mDP
USB Type C

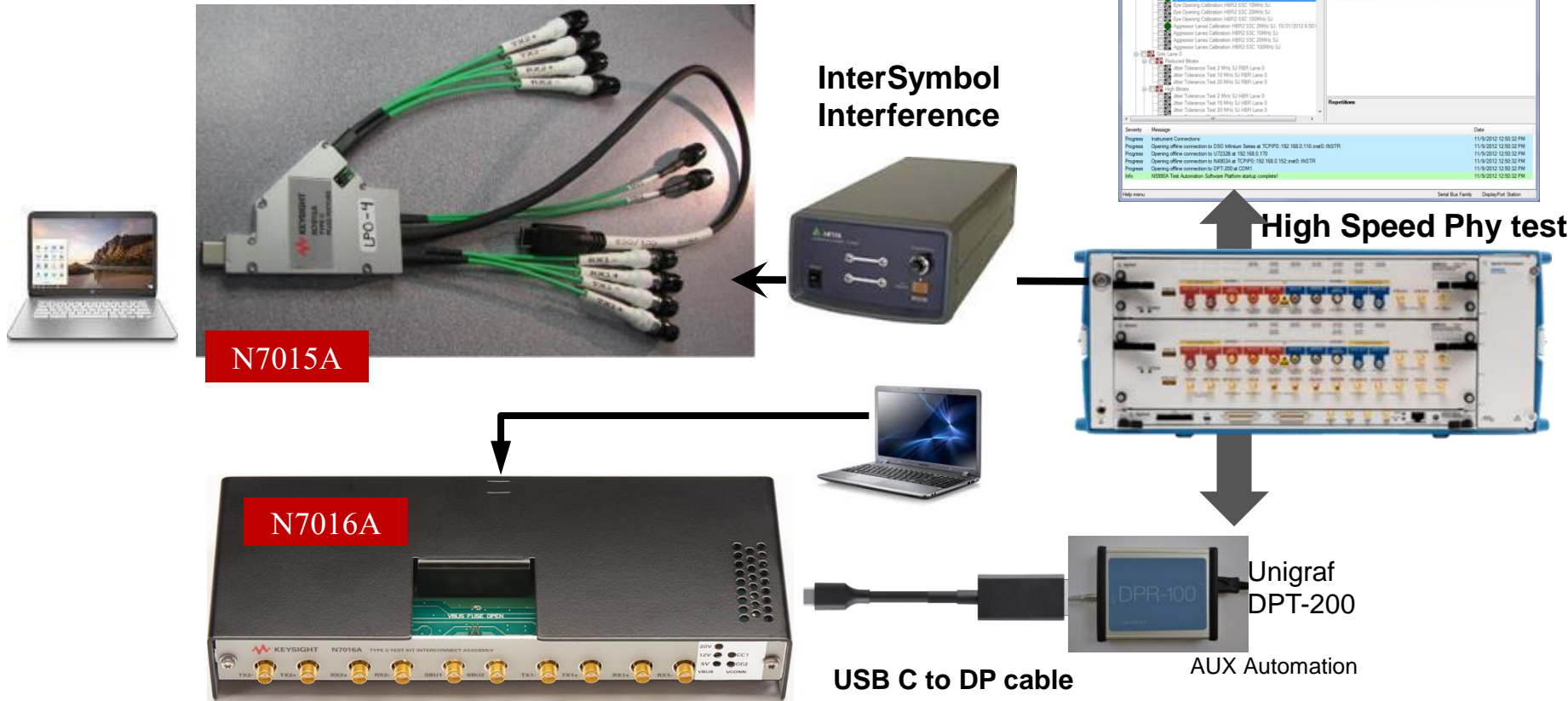
Math performed on
oscilloscope on TP2
acquisition



TX Test Setup for DP over USB Type-C



RX Test Setup for DP over USB Type-C



Keysight DisplayPort 1.3 Solutions and Solution Elements

Source Test Solution



Computer Motherboards,
ICs, Graphic Cards



DSO V series Infiniium
Real Time Oscilloscopes



Unigraf DPR-100
For automation



U7232D DisplayPort
Compliance Test SW

STD/mDP



Wilder TPA

USB C



N7015A TPA

Media Testing



Cables, PC Boards,
Connectors



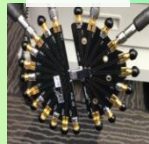
E5071C VNA

STD/mDP



BIT-DP-CBL-0002

USB C



Luxshare Rec

Sink Test Solution



PC Monitors



Artek CLE1000



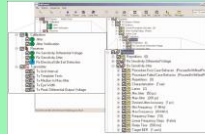
M8020A JBERT



N4915A-006
DP ISI Generation



Unigraf DPT-200
for Automation



N5990A Rx
Compliance
Test SW

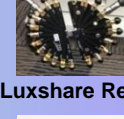
STD/mDP



EIT-DP-RTF-0002

Wilder TPA

USB C



Luxshare Rec

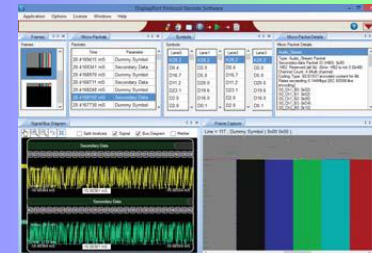
N7015A TPA

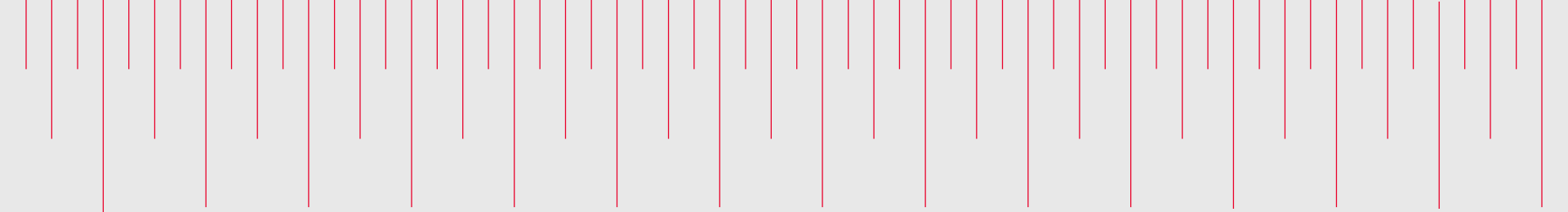
Link Layer & General Solutions

Protocol Debug solution



Granite River Labs
GRL-DP-DEC





USB Type-C Interface and TBT Alt Mode Overview

Thunderbolt 3 Overview

- Announced in Q2 2015
- Uses the Type-C connector
- Channel aggregation: two independent 20Gbps links into one logical 40Gbps link
- Supports other standards through ALT mode

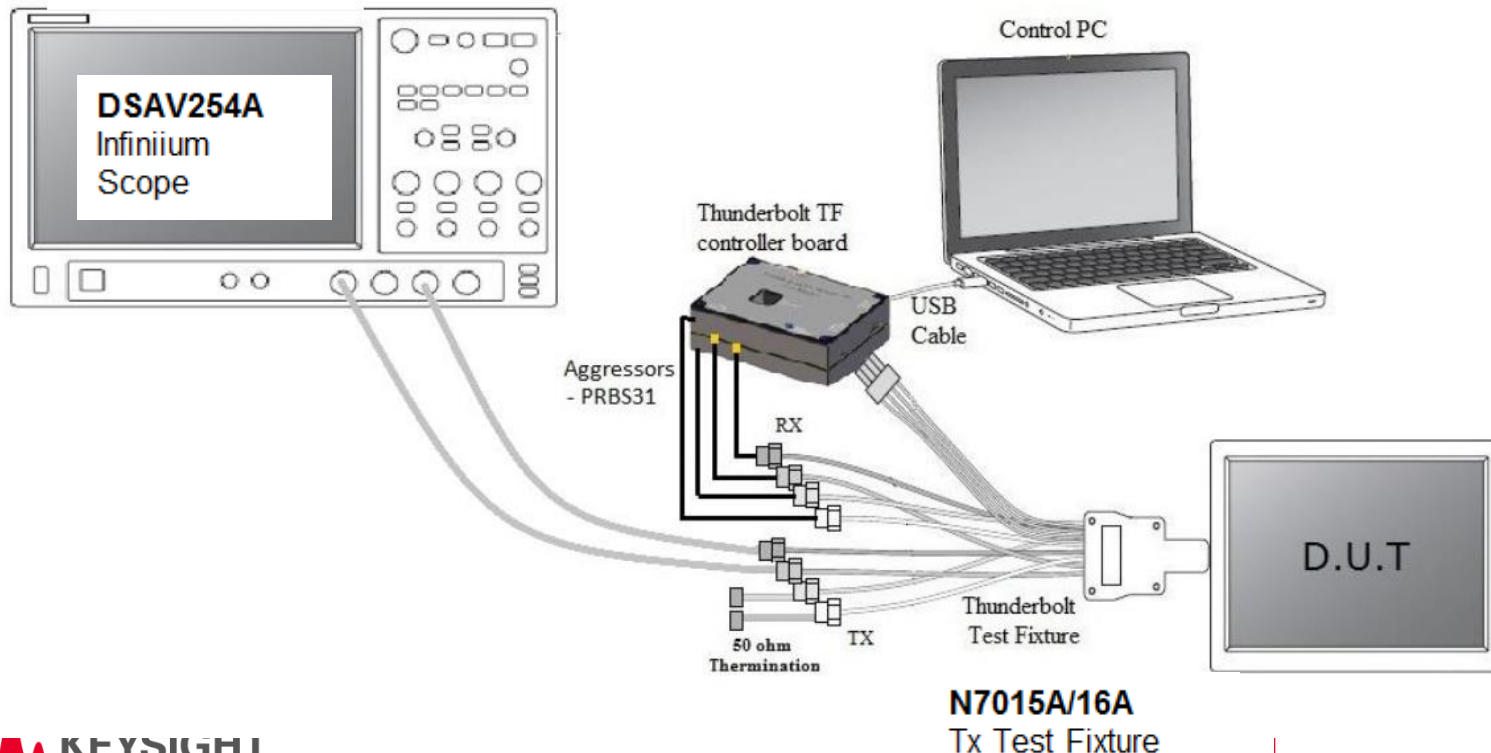


Testing Methodology

- Spec is at v0.7.
- CTS not yet released.
- Testing approach will be similar to Thunderbolt 2
 - Tx, Rx, and Return Loss
- Today, customers with Thunderbolt DUTs need to work with their Intel PAE to meet the design guidelines and send their DUTs to Intel for testing.
- Keysight can help with pre-compliance testing
- Tx testing
 - Initial analysis is that 33GHz minimum BW is required for compliance testing.
 - Silicon characterization will need more BW since the 20/80 risetime can be 10ps.

Thunderbolt 3 Transmitter Test Setup

- 25GHz BW required for compliance testing, more if closer to the silicon
- Thunderbolt-specific SW (Imaginarium, TenLira, TCL, scripts)
- Crosstalk generator
- Type-C test fixture
- UI, SSC, Rise/Fall, Jitter, Eye Diagram Near End/Far End
- New Preset testing and optimization for 10.3G and 20.6G



Thunderbolt 3 Return Loss Test

- DUT output PRBS31 on all lanes with SSC turned on
- Setup the Network Analyzer with automated measurements specific to Thunderbolt 3

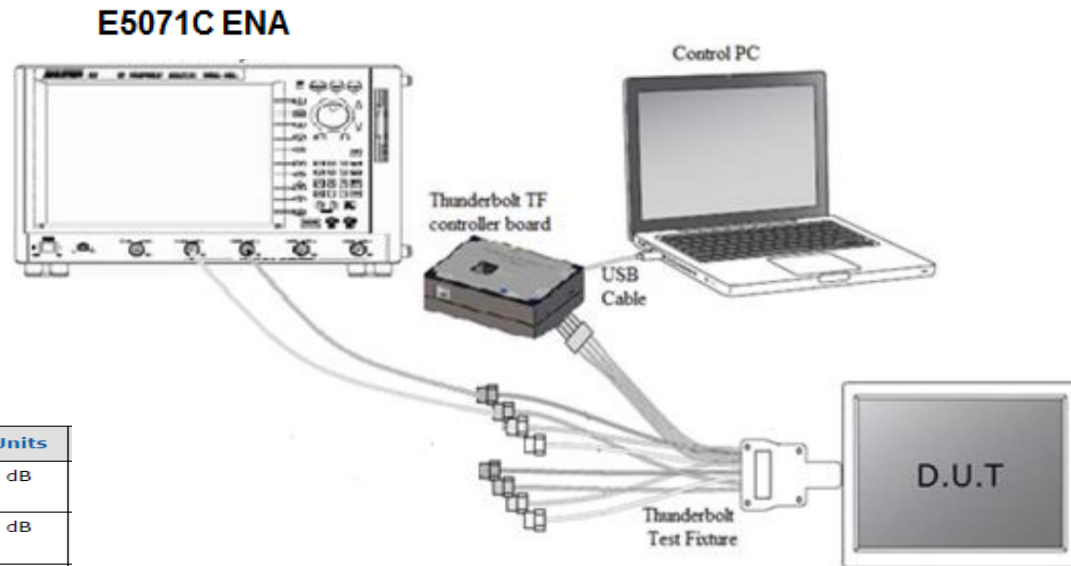
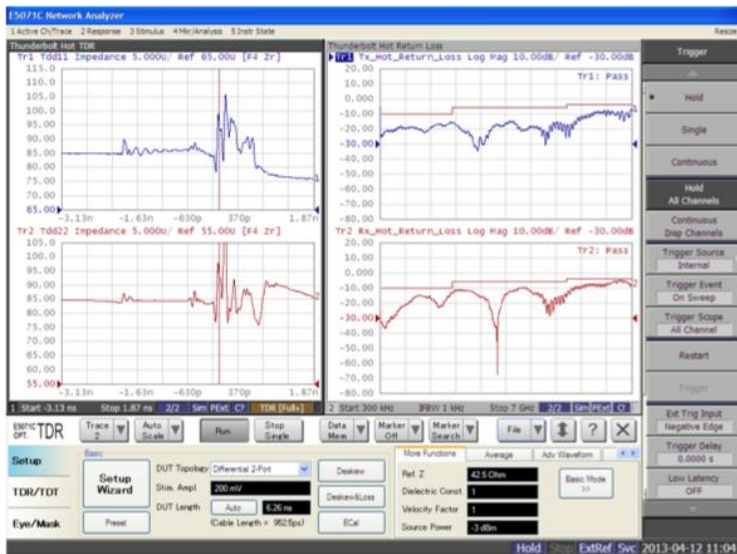
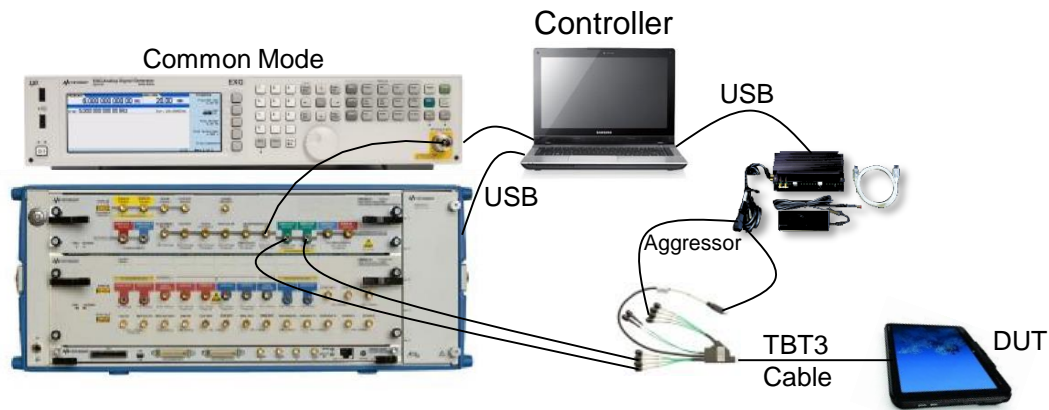
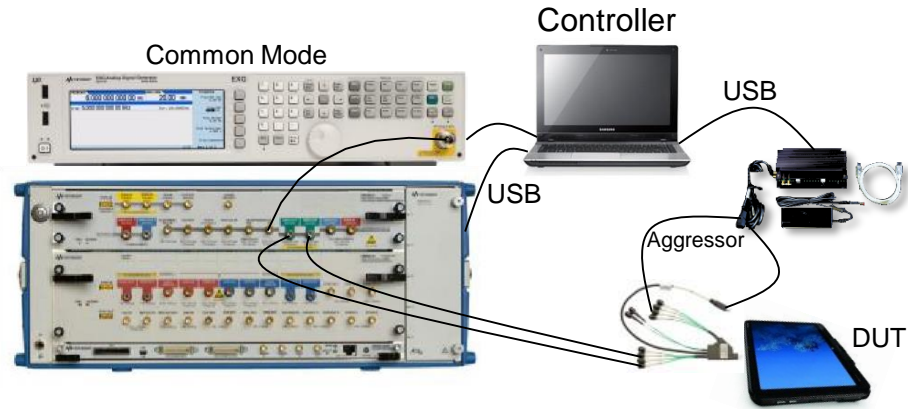


Table 4-6. Host/Device Transmitter Specifications at TP1

Symbol	Description	Min	Max	Units
RL_LF	Return loss, 0.05 – 2 GHz	10		dB
RL_MF	Return loss, 2 – 5.2 GHz	6		dB
RL_HF	Return loss, 5.2 – 7 GHz	4		dB

Test Setup: Case 1 and Case 2 Execution



Thunderbolt 3 – Total Solution

